



# SP X: Re-excitation of Laser-Induced Plasma for Depth Profile Quantitative Analysis of Real Reactor Wall Samples.

**Pavel Veis, Sahithya Atikukke, Shweta Soni, Matej Veis,  
Sanath J. Shetty et al (CU)**



This work has been carried out within the framework of the EUROfusion Consortium, funded by the European Union via the Euratom Research and Training Programme (Grant Agreement No 101052200 — EUROfusion). Views and opinions expressed are however those of the author(s) only and do not necessarily reflect those of the European Union or the European Commission. Neither the European Union nor the European Commission can be held responsible for them.



- LIBS experimental setups
  - VUV-NIR ps/ns LIBS
  - Resonant LIBS, LIBS-LIF, MW LIBS
- Towards Re-excitation of Laser-Induced Plasma
  - Standard CF LIBS & depth profile analysis by ns laser
  - ps versus. ns LIBS - comparison
  - Resonant LIBS for depth profile quantitative analysis (ns laser)
  - MW assisted LIBS for depth profile quantitative analysis
- Conclusions

## REVIEW papers

### - LIBS in nuclear fusion and plasma wall interactions:

Maurya, G.S., Marín-Roldán, A., Veis, P., Pathak, A.K., Sen, P.  
**Journal of Nuclear Materials, 541(2020) 152417**

H. Van der Meiden et al.

**Nucl. Fusion 61 (2021) 125001**

## Conf. talks:

Veis P., Marín Roldán A., Dwivedi V., Atikukke S., Veis M.:  
LIBS for the analysis of fuel retention and PFM  
characterization, **Invited talk, LIBS for Extreme Applications,  
Peking, Dec. 2022**

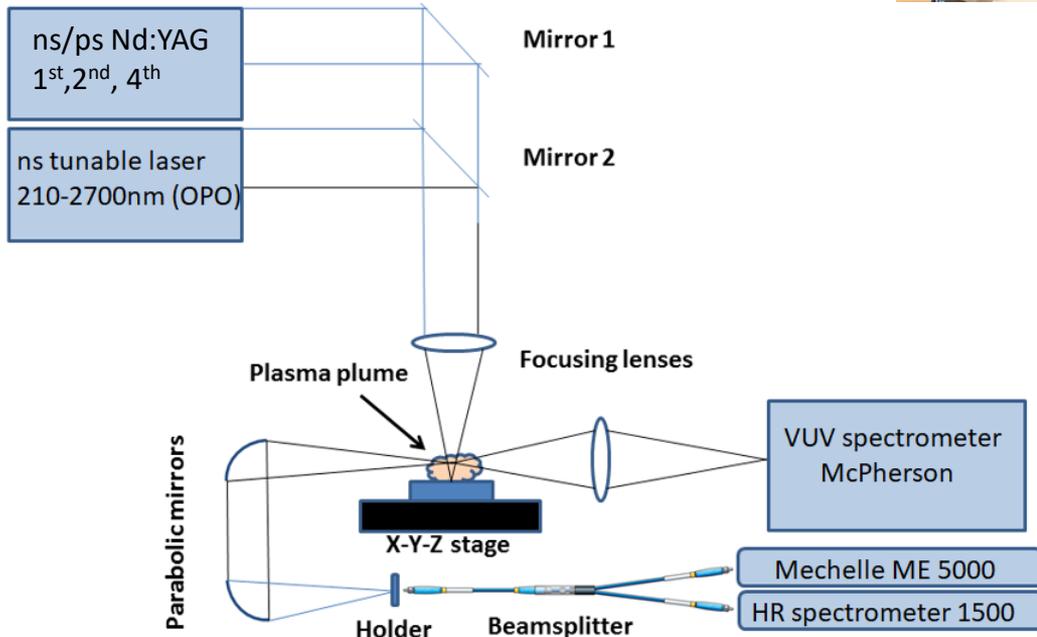
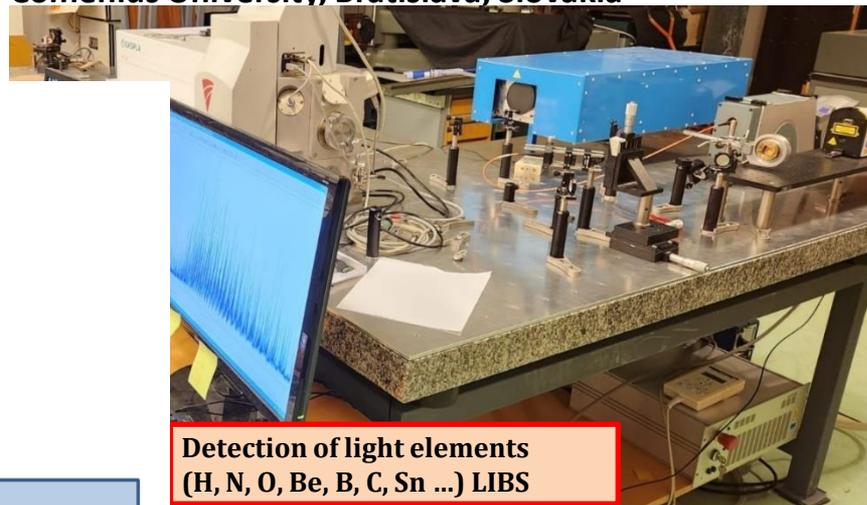
Marín Roldán A., Dwivedi V., et al: LIBS of PFM:  
characterization and fuel retention studies, **talk, LIBS conf.,  
Bari, Sep. 2022**

Veis P., et al, Calibration Free LIBS for Depth Profile Analysis  
of Impurities, Migrated Material and Retained Fuel in Fusion  
Relevant Materials, **Invited talk, NLIBS, Tampere, Mar. 2024**

# LIBS experimental setups – LIBS VUV/NIR, R-LIBS, LIF



Nd:YAG ns laser (Quintel, Brilliant, CFR 200) ,Nd:YAG ps laser,  
tunable (210-2700 nm) OPO ns laser (EKSPLA NT342C-10-SH)

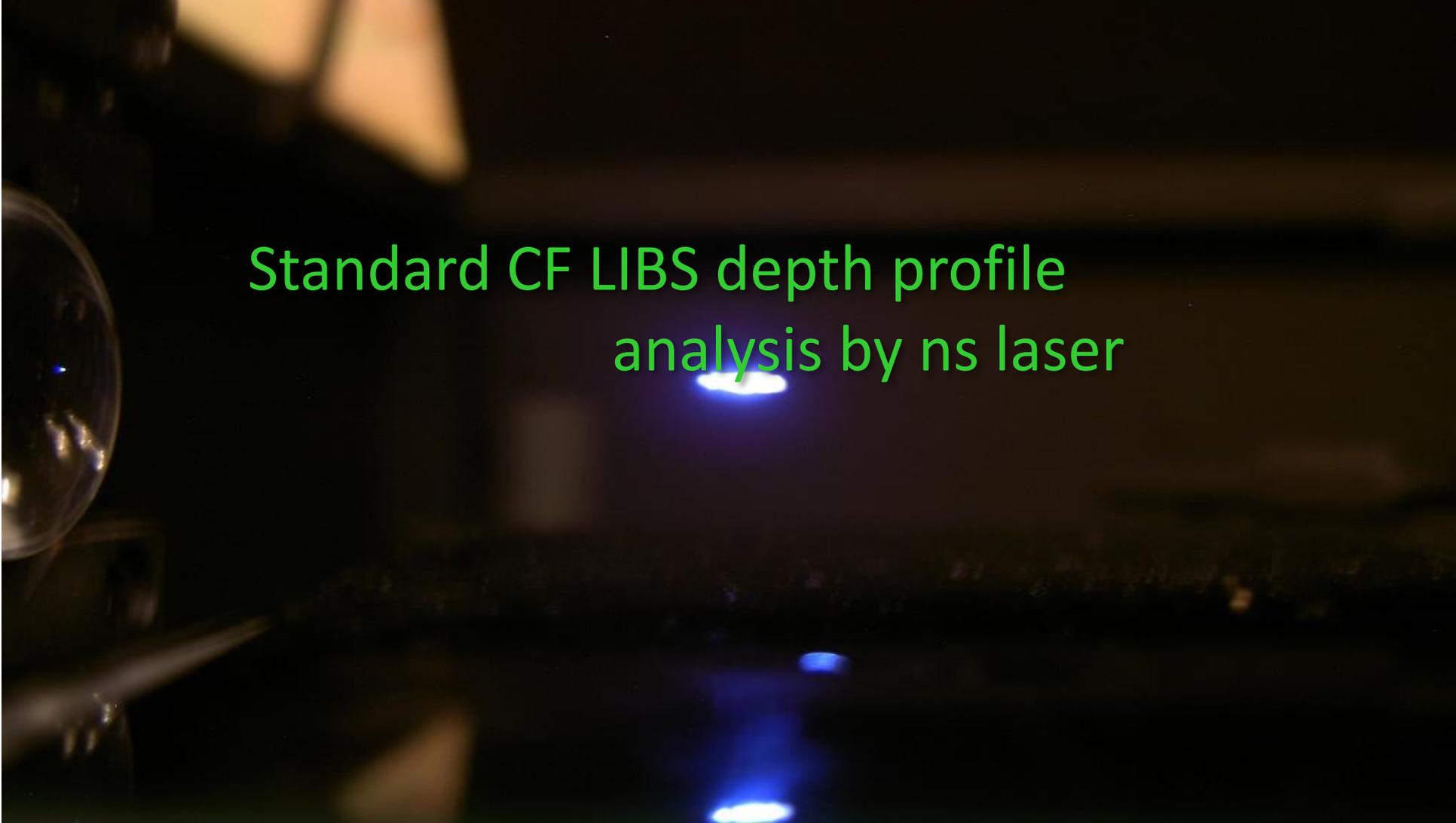


Detection of light elements  
(H, N, O, Be, B, C, Sn ...) LIBS

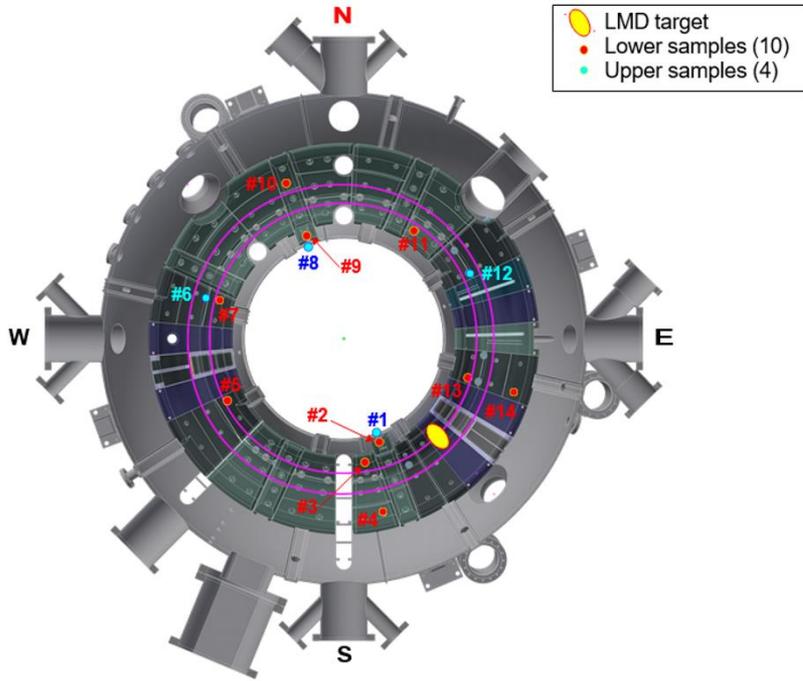
Broadband spectra  
LIBS, CF LIBS  
 $T_e, n_e$   
Molecular spectra  
 $T_{rot}, T_{vib}$

Echelle spectrometer (Andor ME500, 200-975 nm)  
VUV spectrometer (McPherson, 115 -300 nm)  
High resolution spectrometer (THR 1500 Jobin Yvon)  
Equiped with iCCD and EMCCD cameras (Andor)

1. Trace element detection in complicated matrixes (Mo, W, Fe...)
2. Spectral lines profiles: Stark broadening =>  $n_e$   
Stark and isotopic shifts, D/H ratio

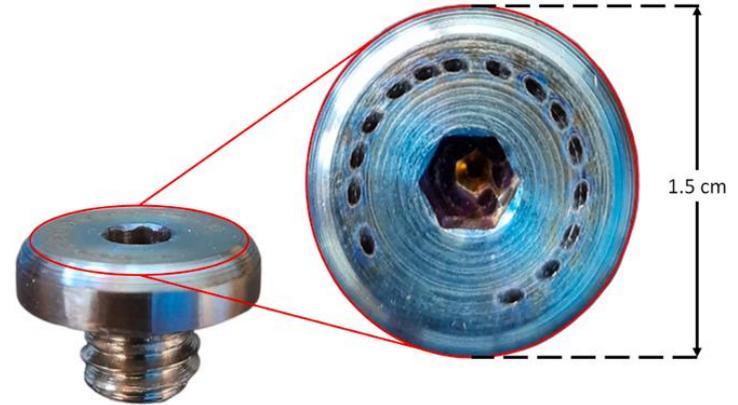
The image shows a dark, possibly laboratory or industrial setting. A bright blue laser beam is visible, entering from the bottom center and reflecting off a surface, creating a vertical path of light. To the left, a circular, metallic-looking lens or mirror is partially visible. The overall scene is dimly lit, with the primary light source being the laser.

Standard CF LIBS depth profile  
analysis by ns laser

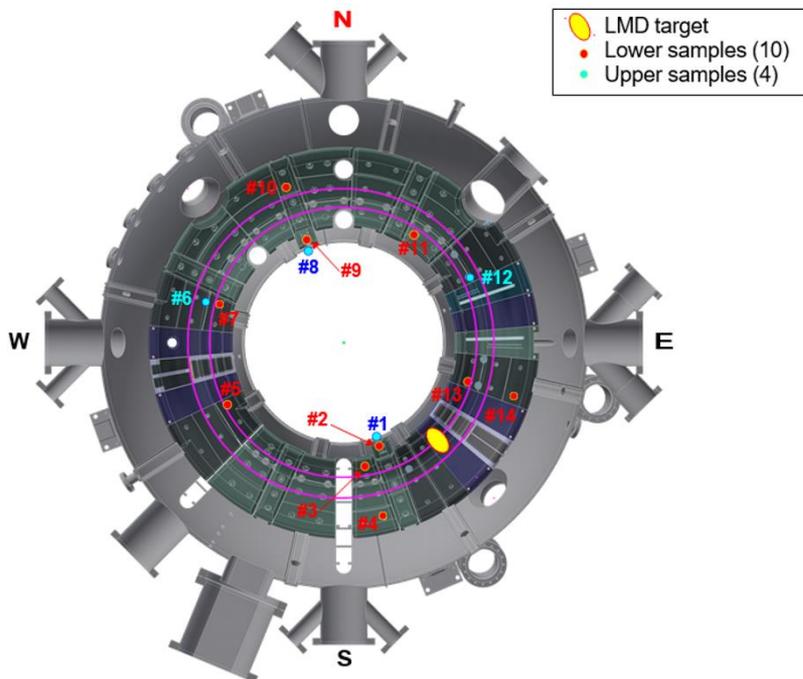


P. Veis, S. Atikukke *et al.*, NME, 25 (2020) 100809

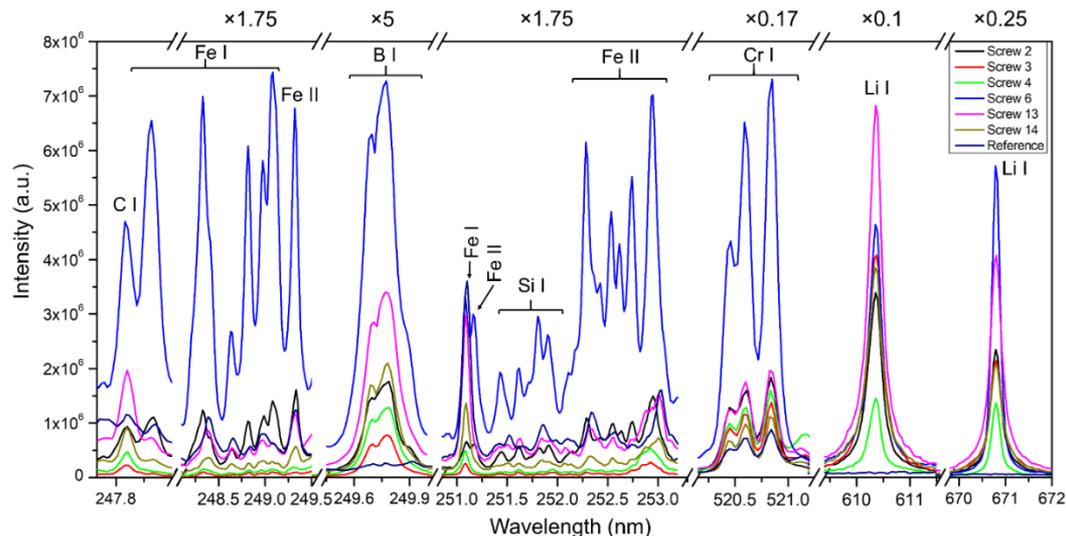
## Screws from COMPASS TOKAMAK CF LIBS in air at atm. pressure



Nd:YAG ns laser @ 1064 nm, Quantel, 13.5 mJ,  
ME5000, Andor, iCCD camera (iStar's DH743)  
Delay and gate width and - 1.5  $\mu$ s and 3  $\mu$ s



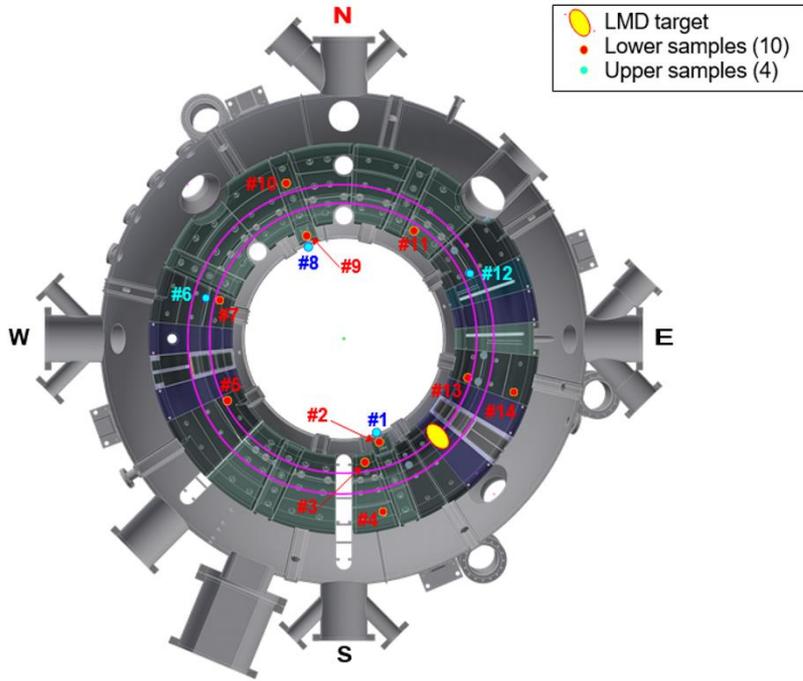
## Screws from COMPASS TOKAMAK CF LIBS in air at atm. pressure



Nd:YAG ns laser @ 1064 nm, Quantel, 13.5 mJ,  
ME5000, Andor, iCCD camera (iStar's DH743)  
Delay and gate width and - 1.5  $\mu$ s and 3  $\mu$ s

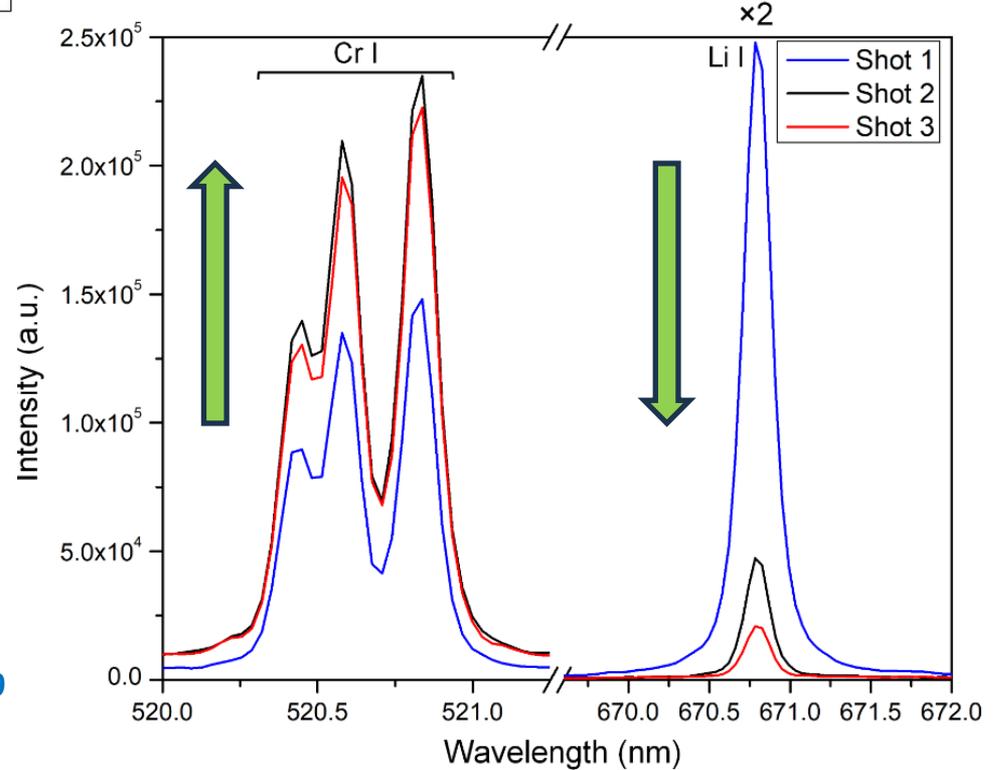
P. Veis, S. Atikukke *et al.*, NME, 25 (2020) 100809

# Depth Profile



P. Veis, S. Atikukke *et al.*, NME, 25 (2020) 100809

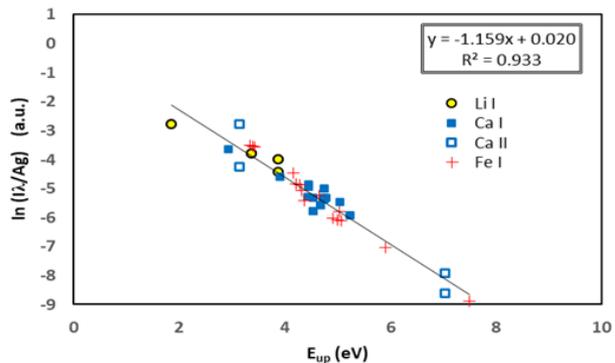
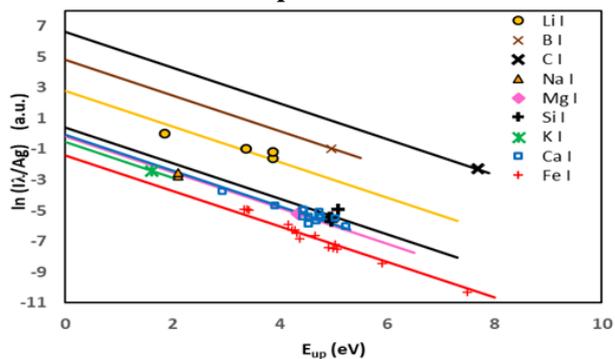
## Screws from COMPASS TOKAMAK CF LIBS in air at atm. pressure



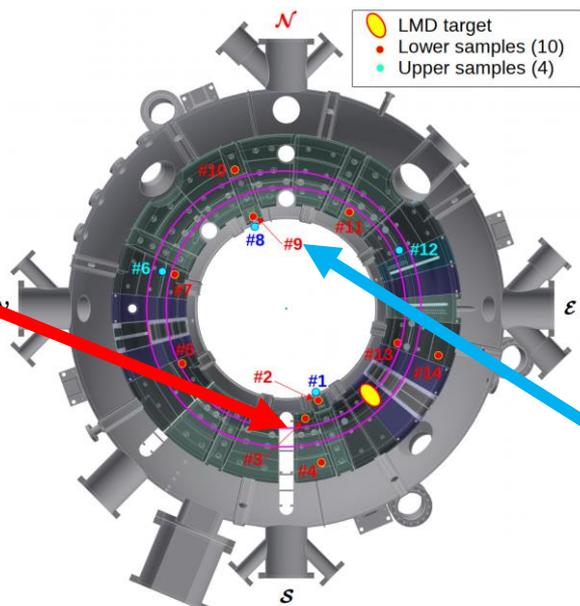
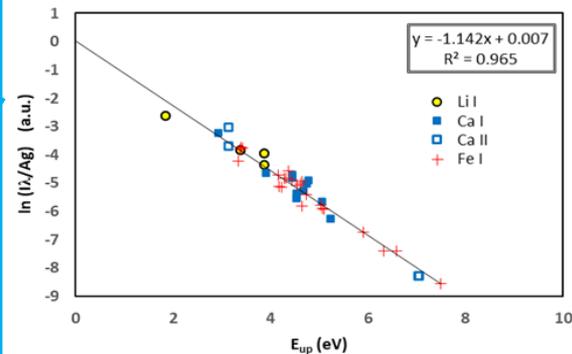
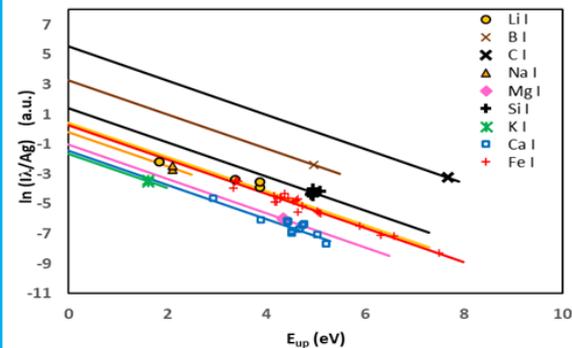
# CF LIBS and depth profile analysis – Li campaign



Saha-Boltzmann plot for screw no. 3:



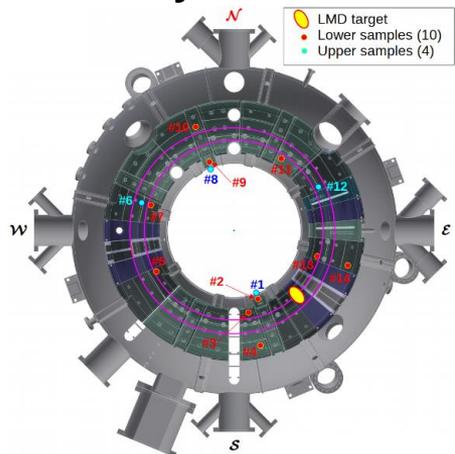
Saha-Boltzmann plot for screw no. 9:



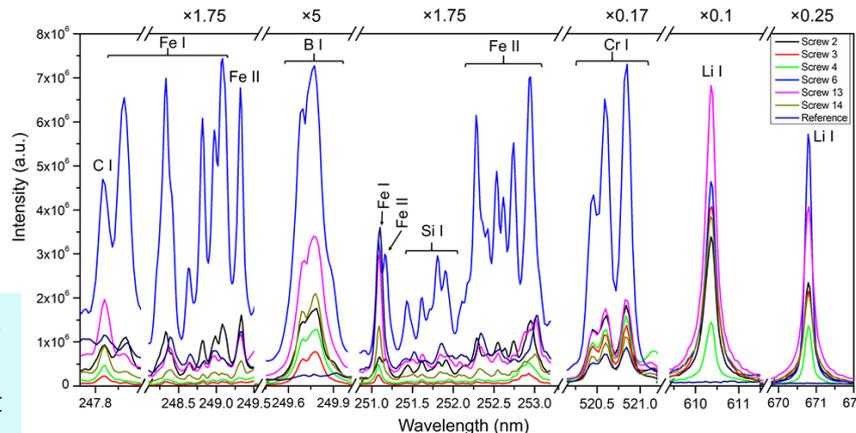
# CF LIBS and depth profile analysis – Li campaign



## Analysis of wall impurities on Ni Cr screws



- Screw 3, 12, 13 and 14 has highest Li (in %) content
- Screw 1,8 and 11 have lowest Li (in %) content
- Screws 3,13 and 14 – closest to LM divertor
- Screw 8 and 9 - farthest

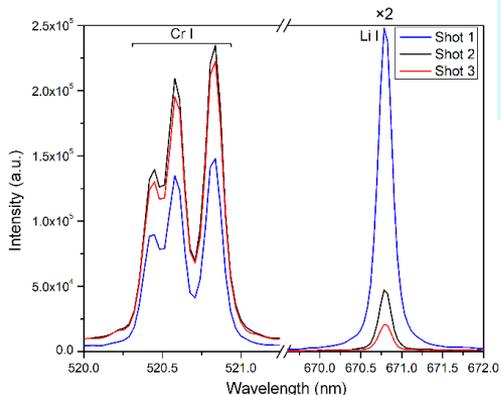


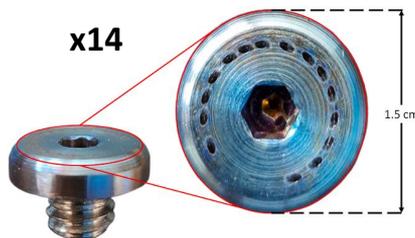
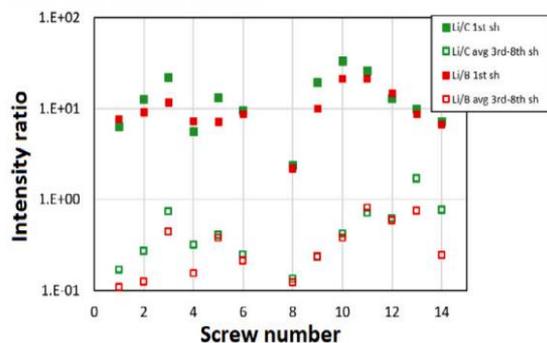
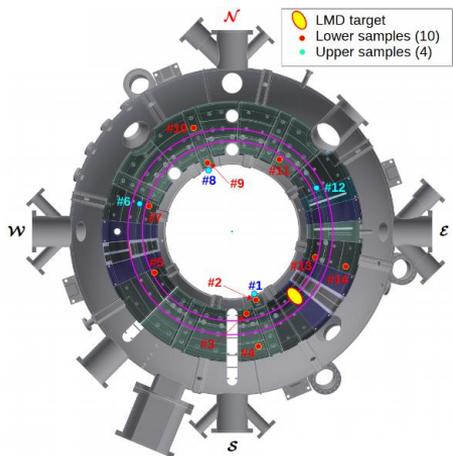
Experimental LIBS spectra of Li I at gate width 3  $\mu$ s, gate delay: 1.5  $\mu$ s

P. Veis, S. Atikukke *et al.*, NME, 25 (2020) 100809

### Atomic percentages for Li, B, C, and Fe. N denote the number of the screw.

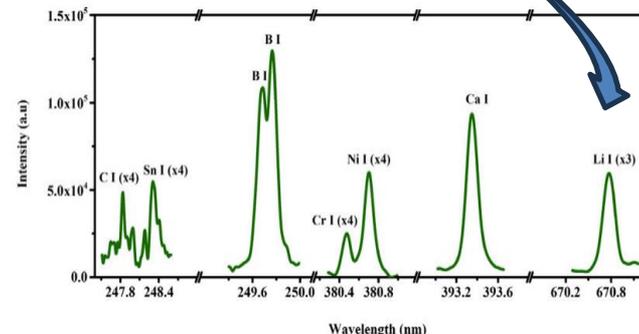
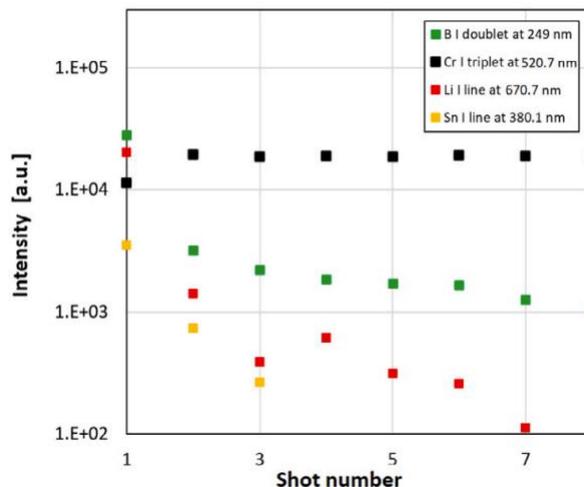
N	1	2	3	4	5	6	7	8	9	10	11	12	13	14
Li	0.4	2.3	7.3	1.2	1.1	1.0	2.4	0.3	1.9	2.1	0.3	10.6	8.6	5.2
C	89.3	89.3	82.9	88.4	89.3	90.5	87.5	94.2	91.3	89.3	93.2	73.3	77.3	83.4
B	10.3	8.4	9.8	10.3	9.6	8.6	10.1	5.5	6.8	8.6	6.5	16.0	14.1	11.4





## Screws from COMPASS TOKAMAK CF LIBS in Ar 100 mbar pressure

- What is the Li/Sn quantity ratio in the deposited layer?
- Ln is easy to detect.
- What is the minimal Sn quantity, which we will be able to be detected in complicated matrix of Cr-Ni-(Fe)?

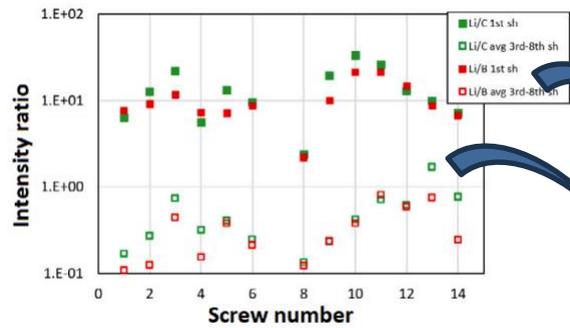
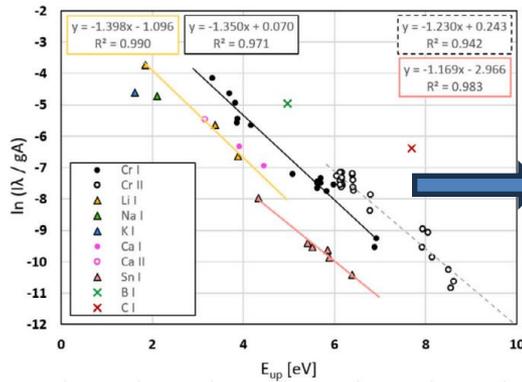
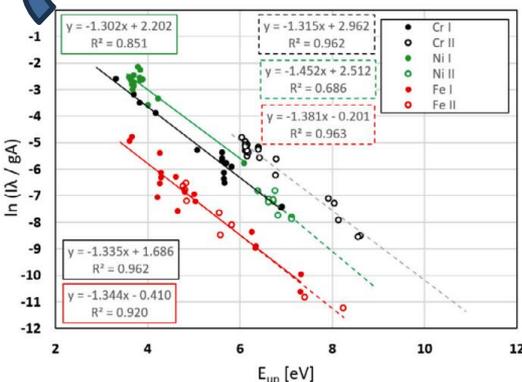


S.J.Shetty, M. Veis et al., NME 37 (2023) 101547

# CF LIBS depth profile analysis – LiSn campaign



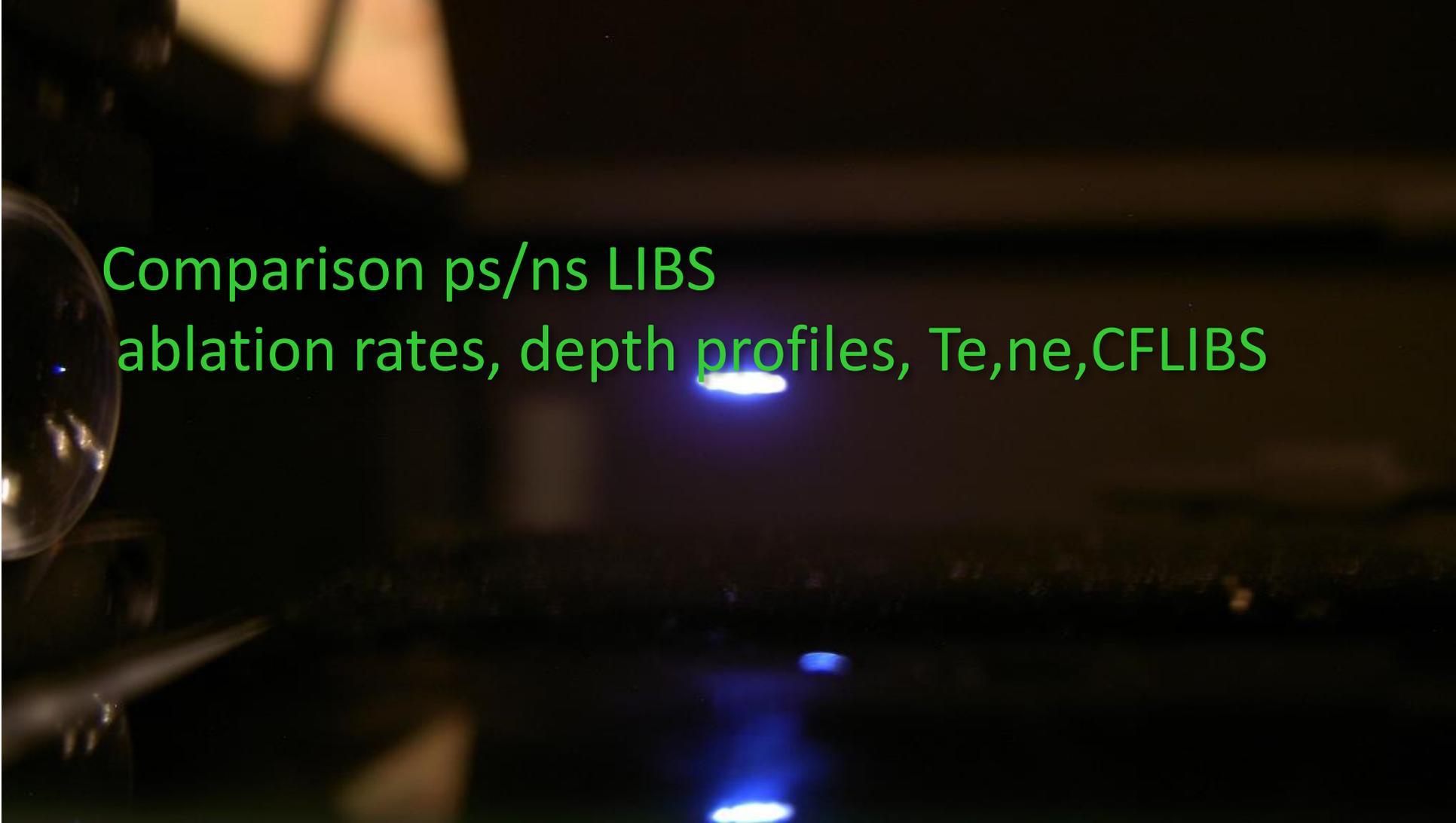
	T1	T2	T3	T4	MIN	MAX
Shot	3–8	3–8	3–8	3–8	1	1
$T_e$	0.75 ±0.02	0.71 ±0.02	0.76 ±0.03	0.77 ±0.02	0.77 ±0.02	0.77 ±0.01
$n_e$	2.01 ±0.49	1.10 ±0.81	1.74 ±0.57	1.34 ±0.55	1.54 ±0.22	3.00 ±0.20



el.	MIN [%]	MAX [%]	el.	MIN [%]	MAX [%]
Li	0.296 ±0.17	0.810 ±0.26	Ni	13.1 ±0.72	11.0 ±0.56
Sn	0.095 ±0.05	0.234 ±0.1	Fe	1.52 ±0.09	1.54 ±0.10
B	4.35 ±0.36	5.53 ±0.30	Na	0.273 ±0.14	0.473 ±0.16
C	66.6 ±4.64	69.1 ±4.17	K	0.703 ±0.36	0.671 ±0.19
Cr	12.9 ±1.21	10.3 ±0.89	Ca	0.255 ±0.02	0.362 ±0.03

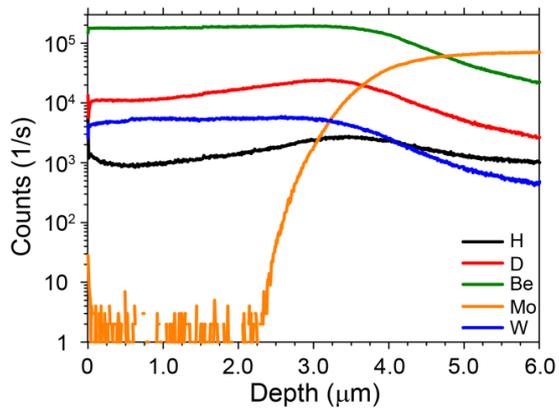
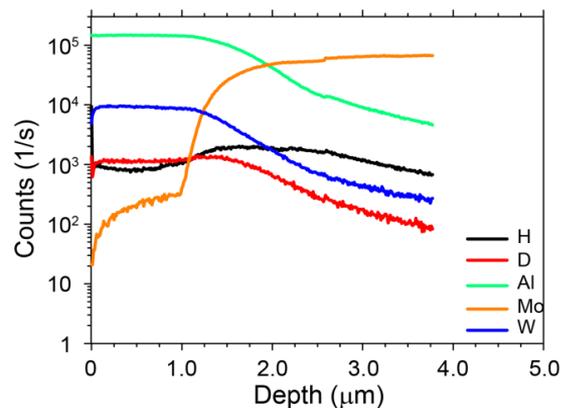
- **CONCLUSION:**
- Main components of the first layer are: C, B, Ni, Cr.
- Measured Sn quantity ranges from 0.1 to 0.23 at.%.
- Measured Li quantity ranges from 0.3 to 0.81 at.%.
- Minimal quantity of Sn to be able to detect is around 0.1 at.%.
- Observed Li/Sn quantity ratio is 3 to 3.5.

S.J.Shetty, M. Veis et al., NME 37 (2023) 101547

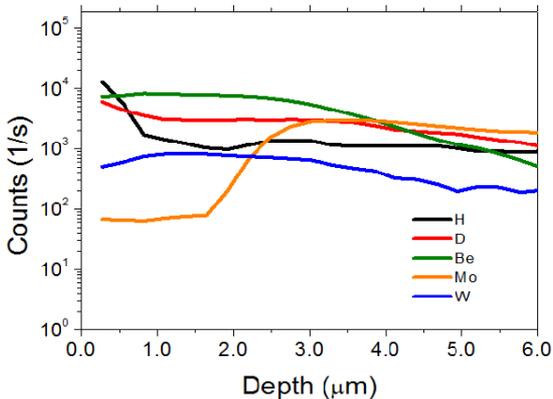
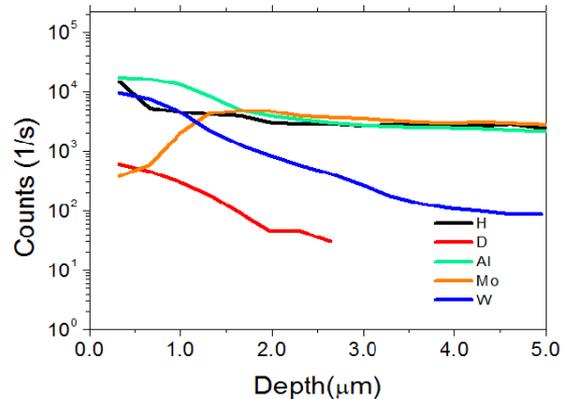
The image features a dark, almost black background. On the left side, there is a metallic, reflective object, possibly a lens or part of a laser system, with some light reflecting off its surface. In the center and lower part of the image, there are several bright blue laser spots or beams, arranged in a vertical line. The text is overlaid on the left side of the image in a green, sans-serif font.

Comparison ps/ns LIBS  
ablation rates, depth profiles, Te, ne, CFLIBS

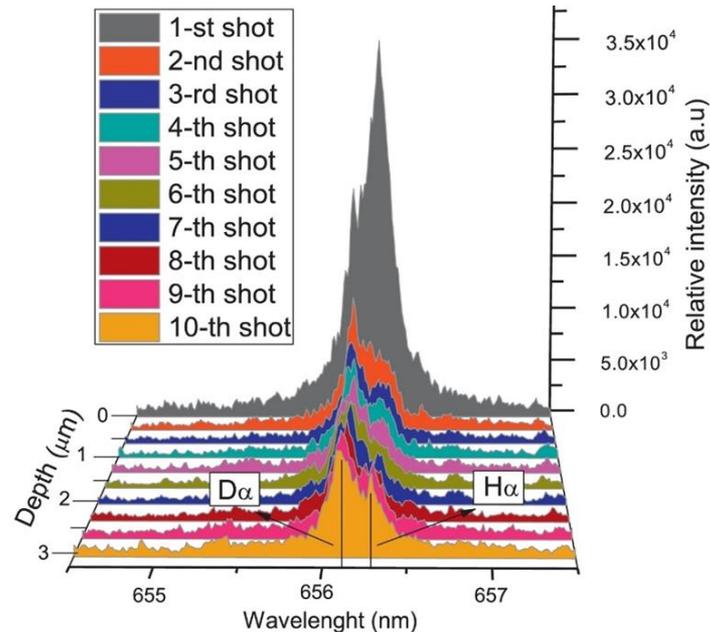
# Depth profiling – comparison LIBS and SIMS – for fuel retention evaluation



SIMS depth profiles of different elements in D-doped Al67W33 (left) and Be67W33 (right) coatings.



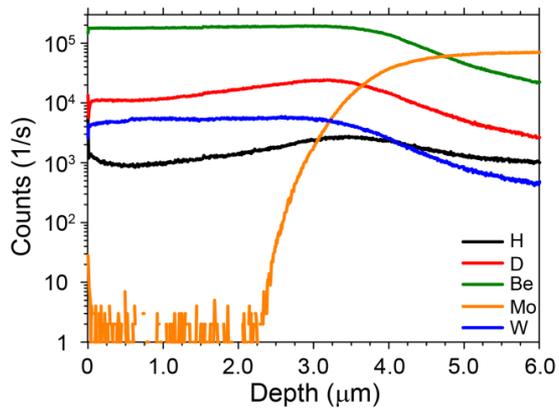
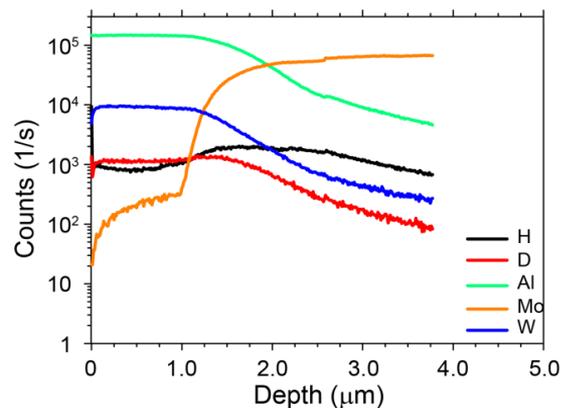
LIBS depth profiles of different elements in D-doped Al67W33 (left) and Be67W33 (right) coatings.



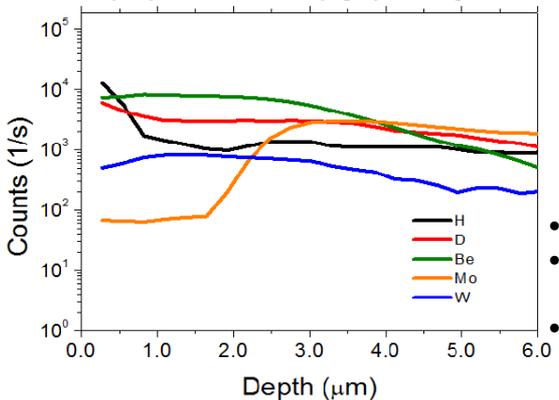
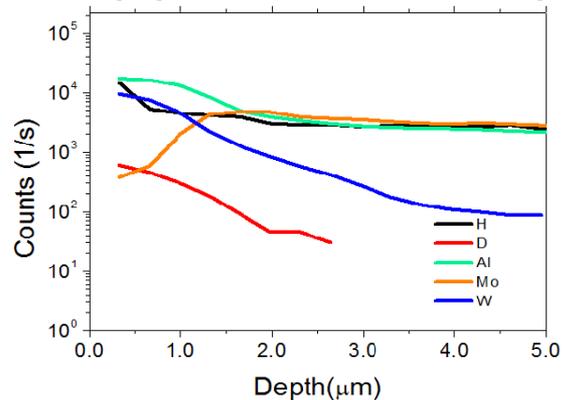
Evolution of Be67W33D LIBS spectra from 1st shot to 10th shot showing the decaying tendency of the D $\alpha$  and H $\alpha$  lines

**M. Suchoňová, P. Veis, et al. ,  
Materials and Energy, 21 (2017) 611**

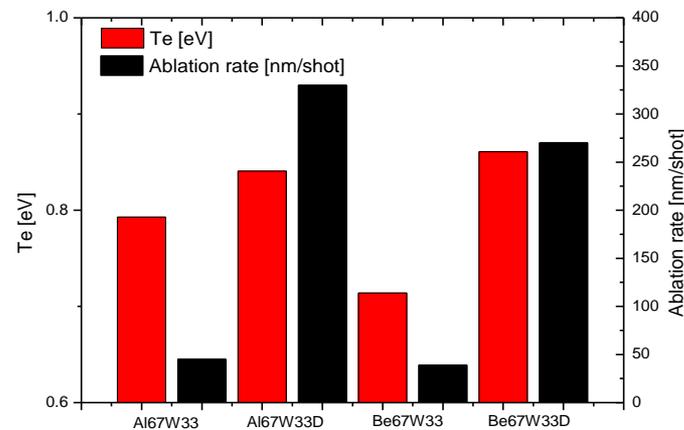
# Depth profiling – comparison LIBS and SIMS – for fuel retention evaluation



SIMS depth profiles of different elements in D-doped Al67W33 (left) and Be67W33 (right) coatings.



LIBS depth profiles of different elements in D-doped Al67W33 (left) and Be67W33 (right) coatings.



Ablation rates for the Al/ Be- W samples with/without D.

Ablation rate [nm/shot]	Al67W33	Be67W33
w/o D	45 ± 8	39 ± 10
with D	330 ± 80	275 ± 35

- We achieved better resolution (nm/pul.) for samples w/o D
- Resolution depends on Te, Ne, sample phys./chem. properties
- LIBS plasma has higher Te for samples with D

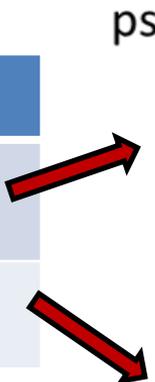
M. Suchoňová, P. Veis, et al.,  
Materials and Energy, 21 (2017) 611

# Comparison ps/ns LIBS – pure W and Mo material



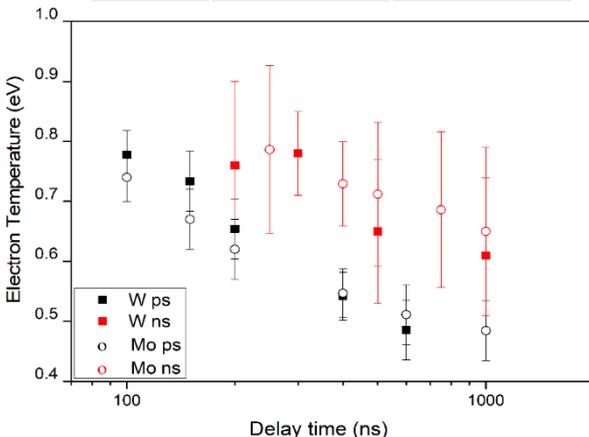
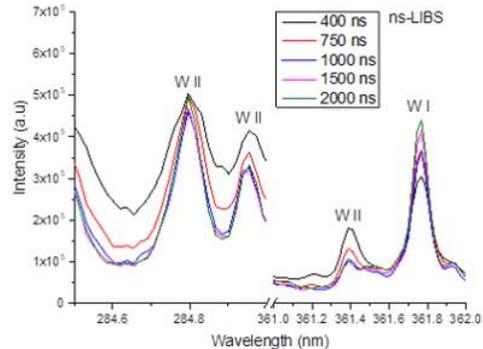
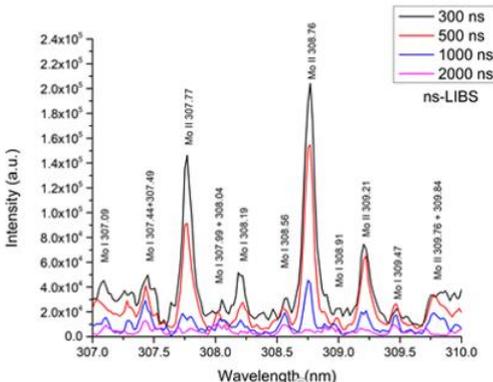
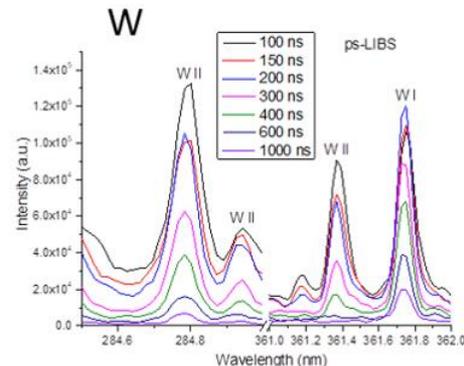
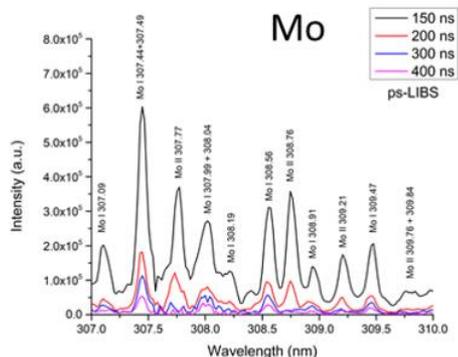
W and Mo as substrates

Regime	Mo	W
ps	85 ± 13 nm/pulse	55 ± 11 nm/pulse
ns	318 ± 63 nm/pulse	207 ± 42 nm/pulse



ps

ns



A. Marín Roldán, P. Veis *et al.*, *Fusion Engineering and Design* 172 (2021) 112898.

# Comparison ps/ns LIBS – pure W and Mo material

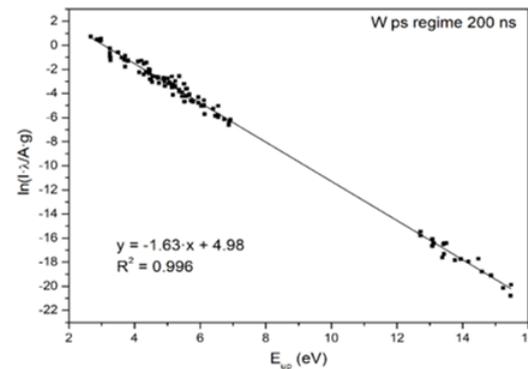
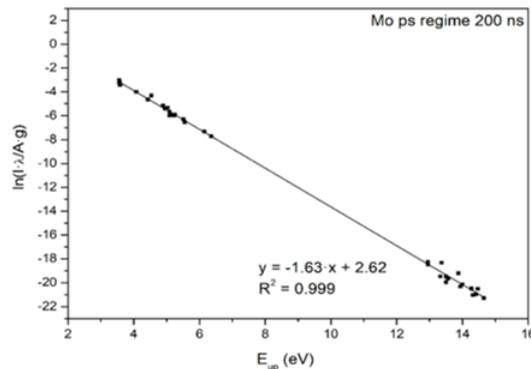


W and Mo as substrates

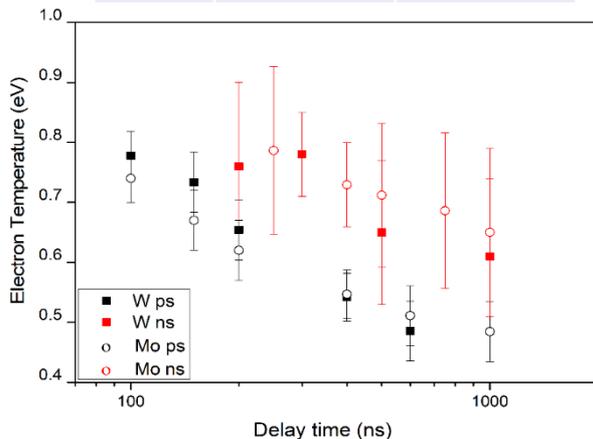
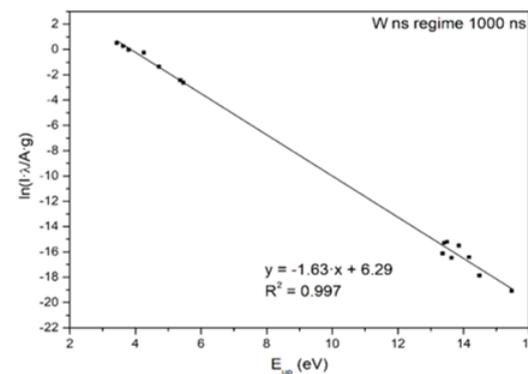
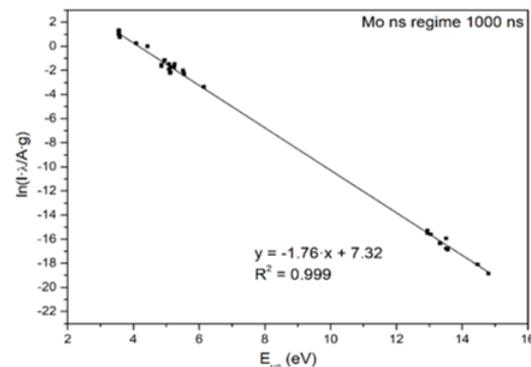
Regime	Mo	W
ps	85 ± 13 nm/pulse	55 ± 11 nm/pulse
ns	318 ± 63 nm/pulse	207 ± 42 nm/pulse



ps



ns

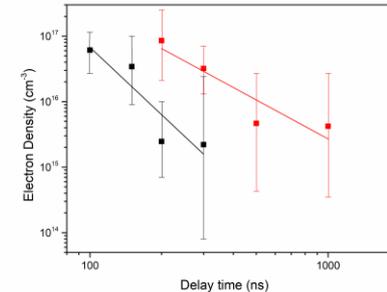
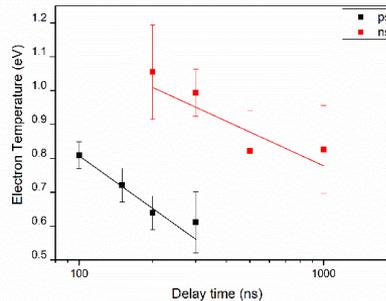
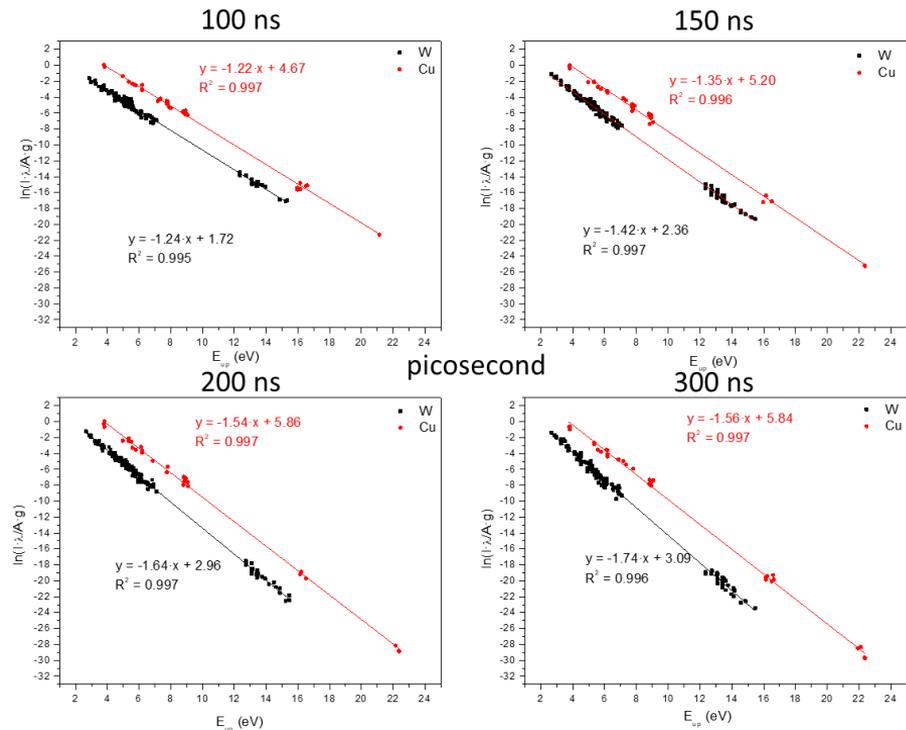


A. Marín Roldán, P. Veis *et al.*, *Fusion Engineering and Design* 172 (2021) 112898.



# Comparison ps/ns LIBS – CF LIBS of W-based alloy

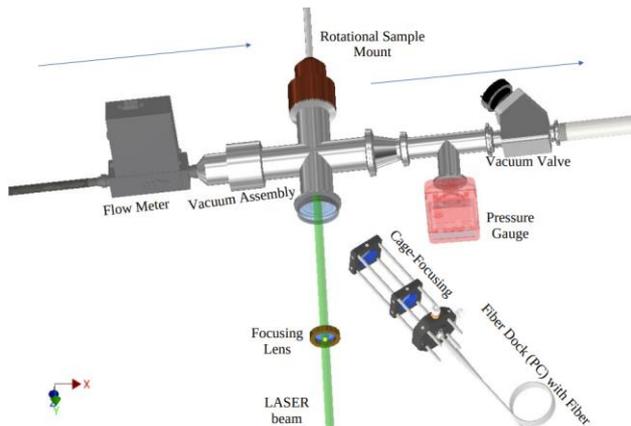
## WCu as W-based alloy



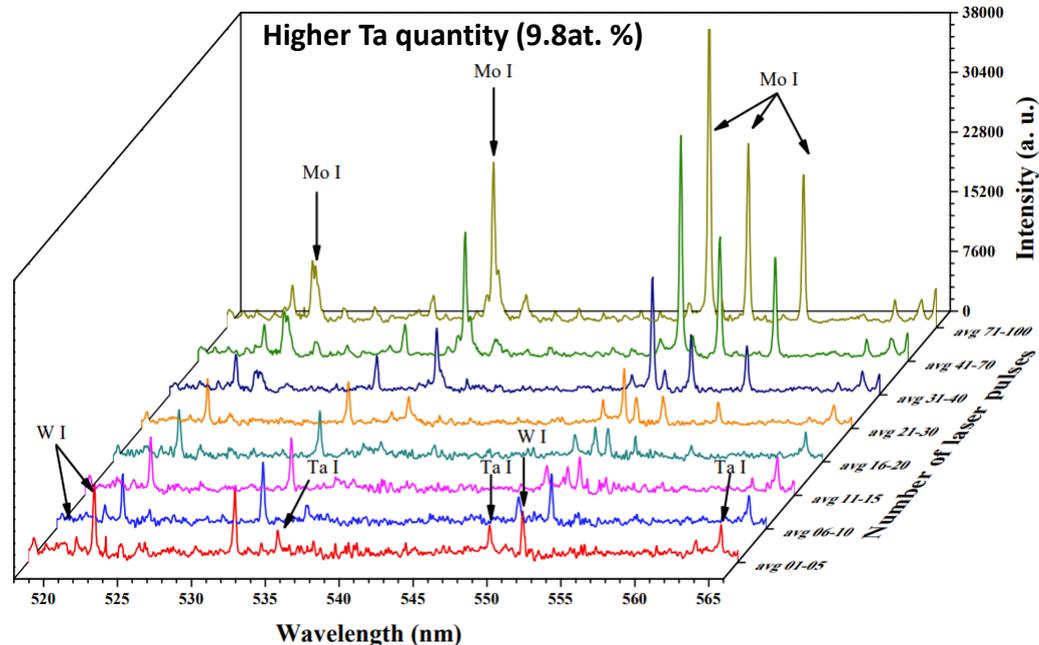
Regime	ps				ns			
	100 ns	150 ns	200 ns	300 ns	200 ns	300 ns	500 ns	1000 ns
<b>W</b>	72.3	70.2	70.0	70.7	73.5	69.5	69.6	70.5
<b>Cu</b>	27.7	29.8	30.0	29.3	26.5	30.5	30.4	29.5

A. Marín Roldán, M. Pisarcík, M. Veis, M. Držík, P. Veis, Spectrochimica Acta Part B: Atomic Spectroscopy 177 (2021) 106055.

# ps LIBS - depth profiling of WTa(D)/Mo



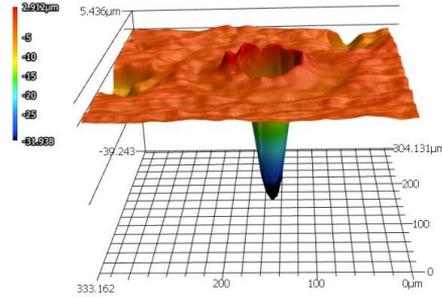
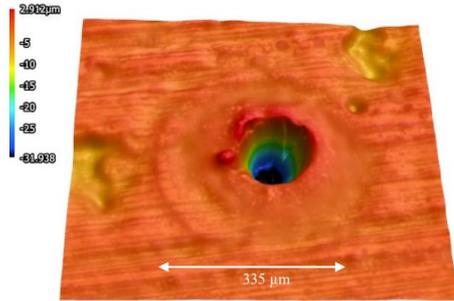
ps LIBS @ 532 nm, 30 ps duration,  
 energy- 1 mj, 3 mj, 10 mj  
 Ar 5 mbar press.,  
 Equal Delay / Gate Time from 200 ns to 450 ns



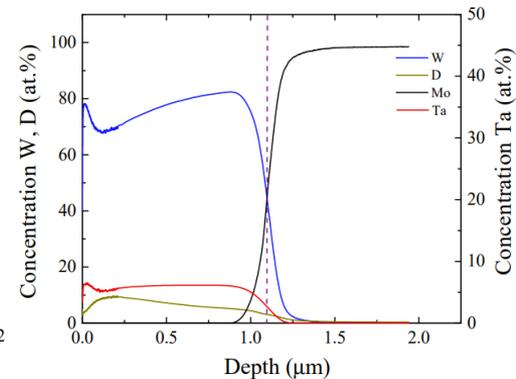
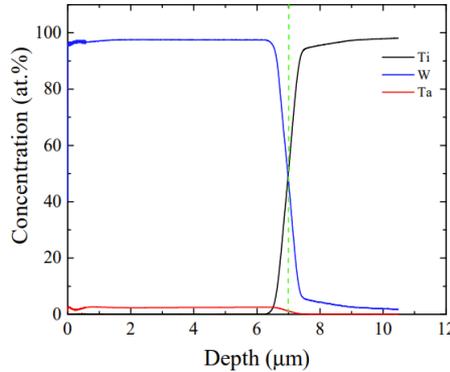
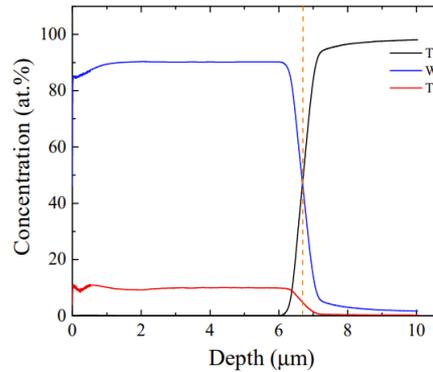
LIBS spectrum of the EU2-72 sample (W I, Ta I, Mo I ines)  
 Delay 200 ns, Gate Time 200 ns  
 thickness- 6.6  $\mu\text{m}$ , approx. 20 shots to cross for 3 mj

Sample Index	Substrate	GDOES Layer Thickness ( $\mu\text{m}$ )	Layer W	Layer Composition (at.%)		
				Ta	D	
EU2-72	Mo	6,68	90.20	9,80	–	
EU2-73	Mo	6,99	97.48	2.52	–	
EU2-75	Mo	1,09	83	7	10	

# ps LIBS - depth profiling of WTa(D)/Mo



Sample Index	Substrate	GDOES Layer Thickness (μm)	Layer Composition (at.%)		
			W	Ta	D
EU2-72	Mo	6,68	90.20	9,80	–
EU2-73	Mo	6,99	97.48	2.52	–
EU2-75	Mo	1,09	83	7	10

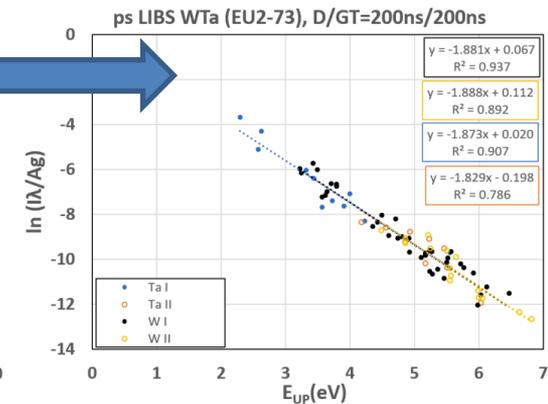
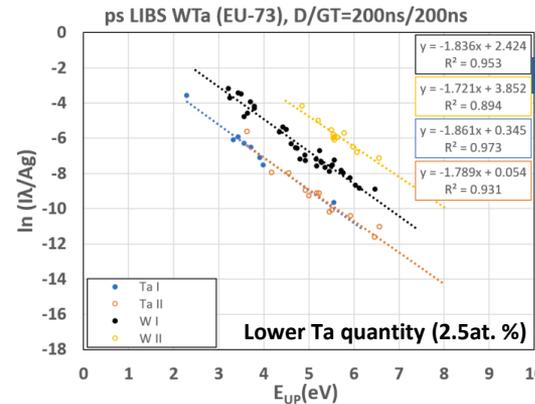
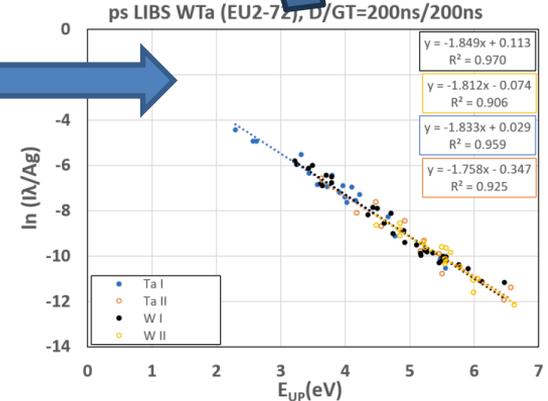
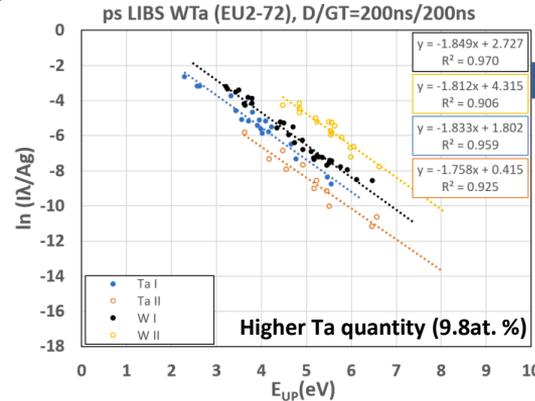


Depth profile measured by GDOES, Confocal microscopy and LIBS:  
 Ablation rate: **min 130 nm/puls (1 mJ) max 290 nm/pulse (3 mJ)**

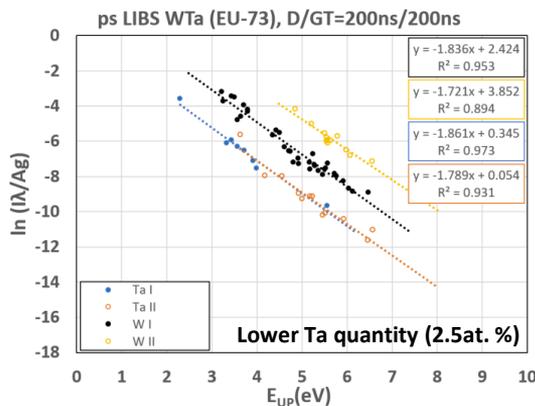
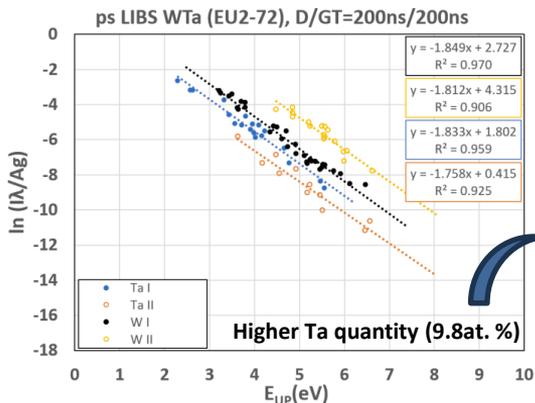
# ps LIBS - depth profiling of WTa(D)/Mo



Sample	Laser Energy (mJ)	Gate Delay (ns)	$T_e$ (eV)	$N_e$ ( $\frac{10^{16}}{cm^3}$ )
EU2-72	1	200	$0.531 \pm 0.045$	1.79
		300	$0.536 \pm 0.047$	1.46
		450	$0.502 \pm 0.081$	0.69
EU2-73	3	200	$0.549 \pm 0.038$	1.69
		300	$0.541 \pm 0.044$	2.35
		450	$0.519 \pm 0.074$	1.99
EU2-73	1	200	$0.533 \pm 0.054$	0.17
		300	$0.517 \pm 0.061$	0.80
		450	$0.503 \pm 0.100$	1.89
EU2-73	3	200	$0.550 \pm 0.045$	1.69
		300	$0.525 \pm 0.065$	0.68
		450	$0.524 \pm 0.080$	1.06



# ps LIBS - depth profiling of WTa(D)/Mo

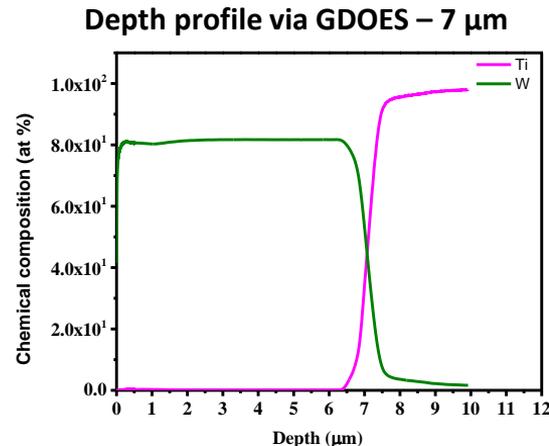
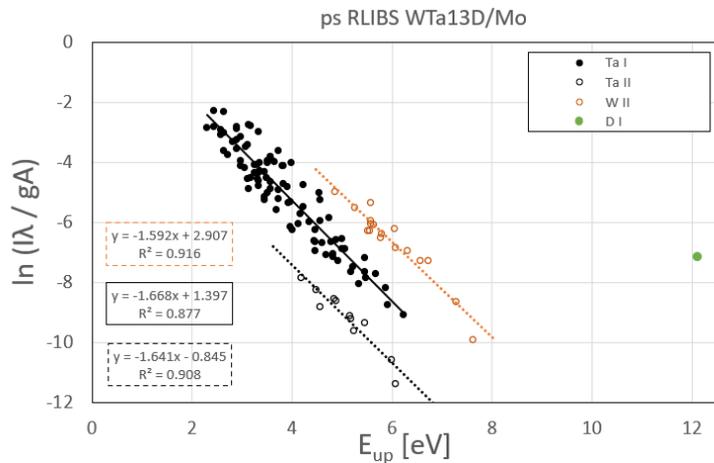


GDOES		CF-LIBS		Rel. Error (%)	
conc. (at. %)		conc. (at. %)			
W	Ta	W	Ta	W	Ta
89.87	10.13	89.87	10.13	1.4	12.7
89.61	10.39	89.61	10.39	1.8	15.1
89.68	10.32	89.68	10.32	2.7	23.9
89.87	10.13	89.87	10.13	1.4	12.7
89.61	10.39	89.61	10.39	1.8	15.1
89.68	10.32	89.68	10.32	2.7	23.9
96.45	3.55	96.45	3.55	1.0	26.8
96.71	3.29	96.71	3.29	1.1	31.1
96.52	3.48	96.52	3.48	1.8	24.1
96.46	3.54	96.46	3.54	0.5	14.1
97.05	2.95	97.05	2.95	0.8	26.1
97.26	2.74	97.26	2.74	0.6	22.7

# ps CF-LIBS non resonant - WTa13D10/Mo sample



Ar 5mbar pressure - at MU Brno



Exp. Conditions: Nd:YAG ps laser @ 532 nm, up to 1-10 mJ, Ar 5 mbar,

D time = G time = 350 ns

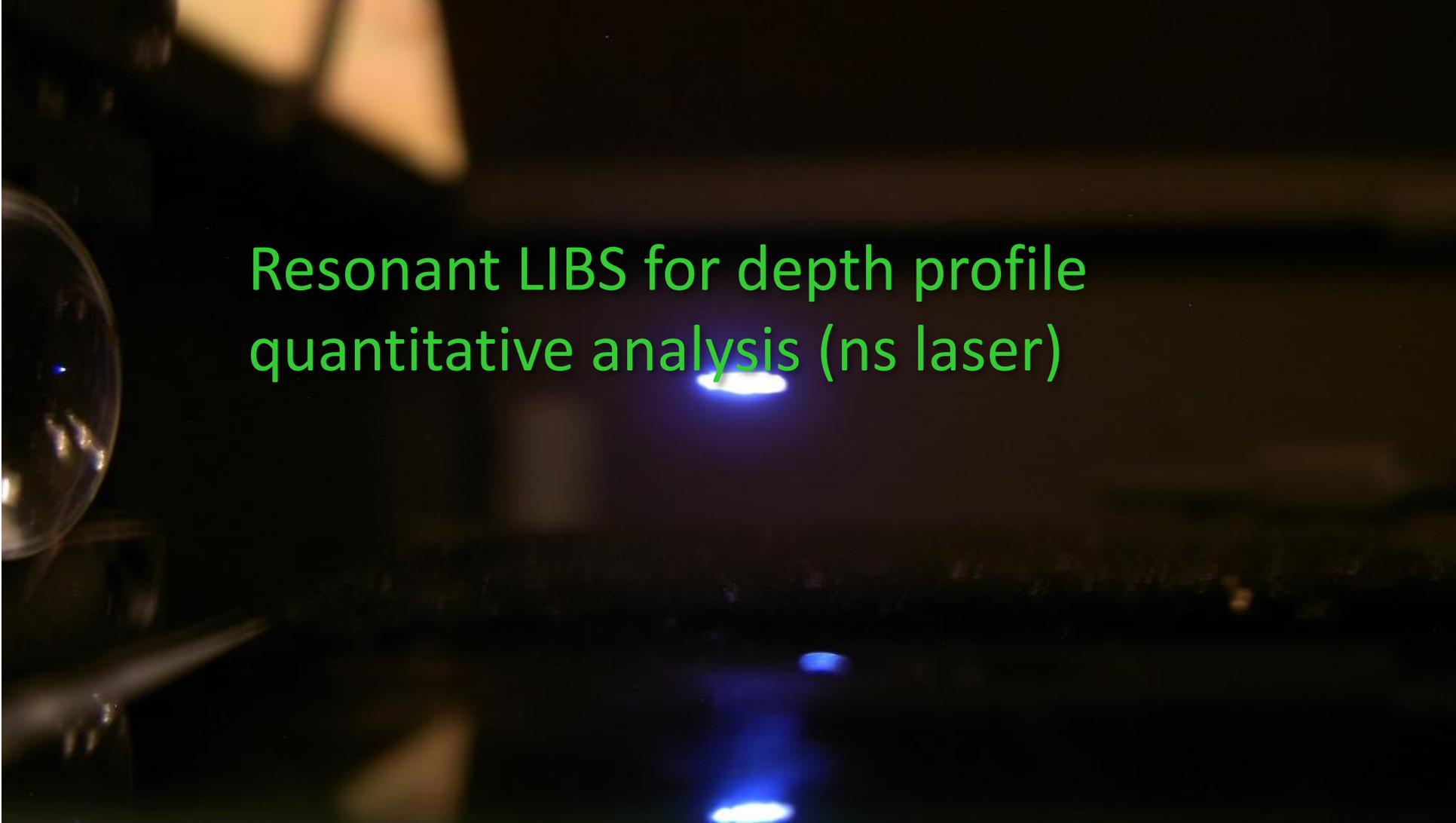
Averaged spectrum from layer. Well separated D/H alpha line.

Selection of lines: self abs. and interference free lines

$T_e = 0.6$  eV averaged from W I-II and Ta I- II

$T_e = 1.04$  eV from Ar I used for quantification of D I

CF LIBS quantification (W 77.8 at.%, Ta 11.5 at.%, D 10.7 at.%)

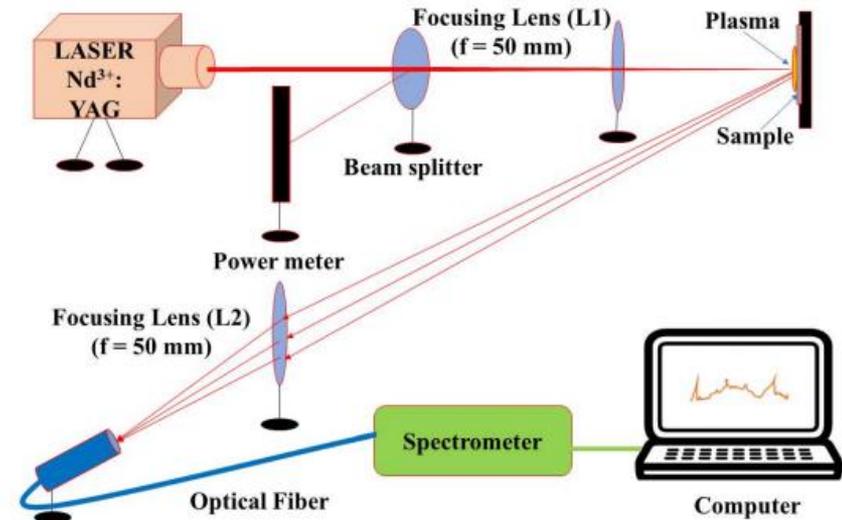
A dark, dimly lit laboratory environment. A bright blue laser beam is visible, entering from the bottom center and reflecting off a surface, creating a vertical path of light. To the left, a large, curved glass lens or component is partially visible. The background is mostly black with some faint, out-of-focus light sources.

Resonant LIBS for depth profile  
quantitative analysis (ns laser)

# Resonant - LIBS depth profile analysis of WTa/Mo samples



- resonant LIBS measurement in collaboration with INFLPR Boucharest (E. Grigore, F. Baiasu) and MU Brno (W. Khan, P. Dvorak).
- ns tunable OPO laser (EKSPLA NT342C-10-SH) pumped with a flash lamps.
- Typical laser beam diameter is 7 mm and has a repetition rate of 10 Hz.
- Time-resolved plasma spectra were obtained using a echelle spectrometer (ME 5000, Andor Technology) and an iCCD camera (iStar DH734, Andor Technology, temporal resolution 5 ns)
- A beam-splitter was placed in the path of laser, that reflect small part (approximately 9% of the laser beam radiation toward power meter to measure the laser energy.



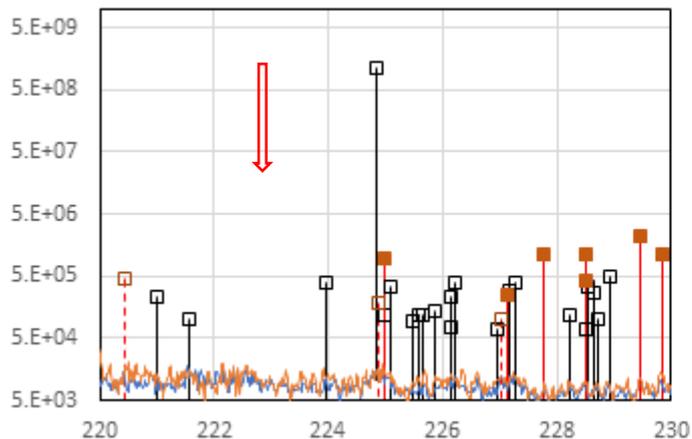
Schematic Diagram of the LIBS setup

# Resonant - LIBS depth profile analysis of WTa/Mo samples



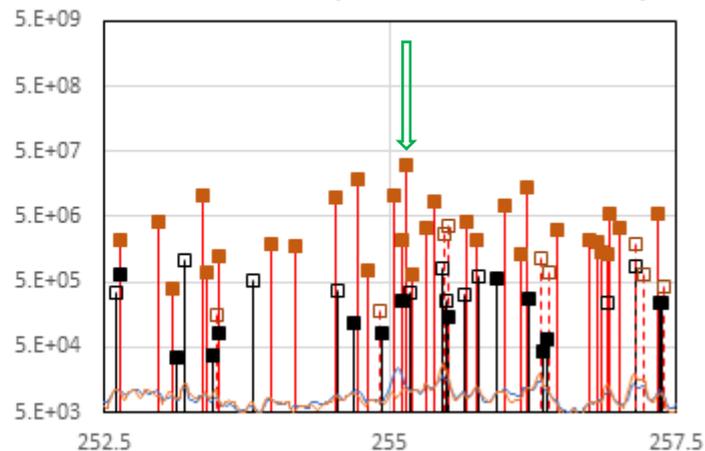
- ✓ LIBS spectrum for sample W20%Ta/Mo (4 $\mu$ m)
- ✓ 150 shots , atm. pressure air

non resonant LIBS (OPO @ 222.75 nm)



- Ta I
- Ta II
- W I
- W II
- R 200-200
- N 200-200

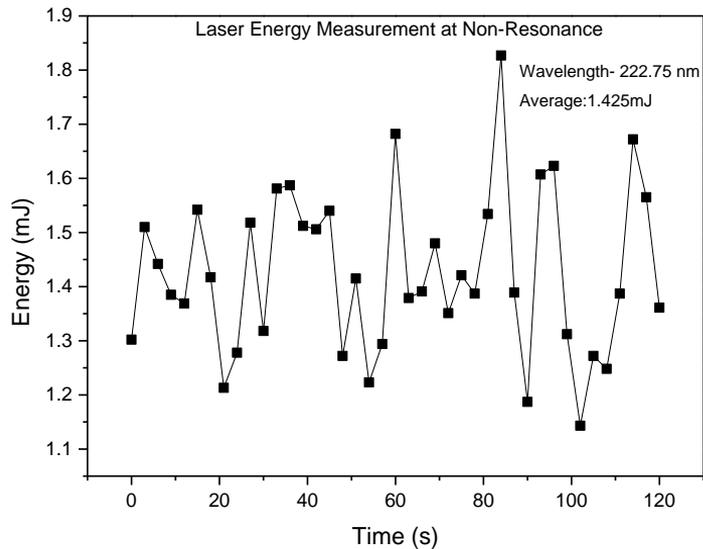
resonant LIBS (OPO @ 255.135nm)



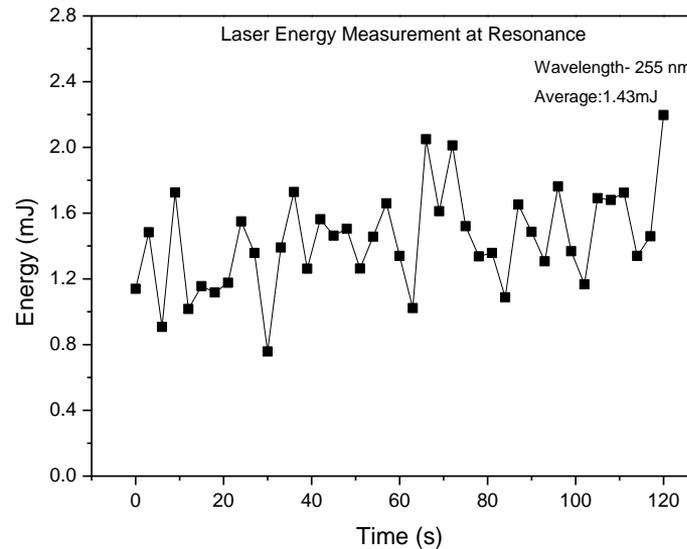
# Resonant - LIBS depth profile analysis of WTa/Mo samples



**Laser energy profile at non-resonance**  
Average energy- 1.425 mJ



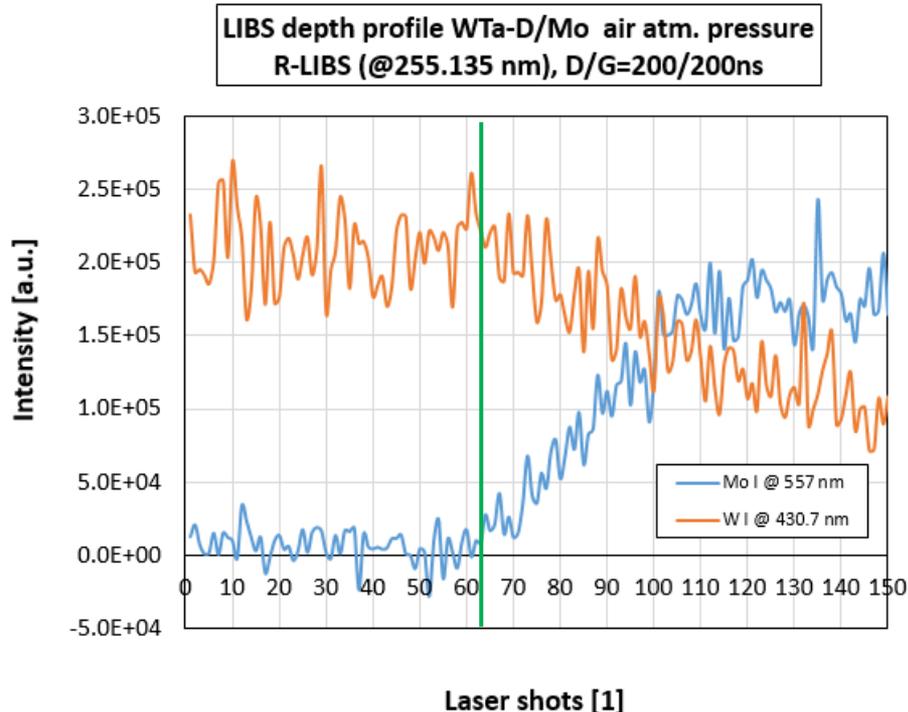
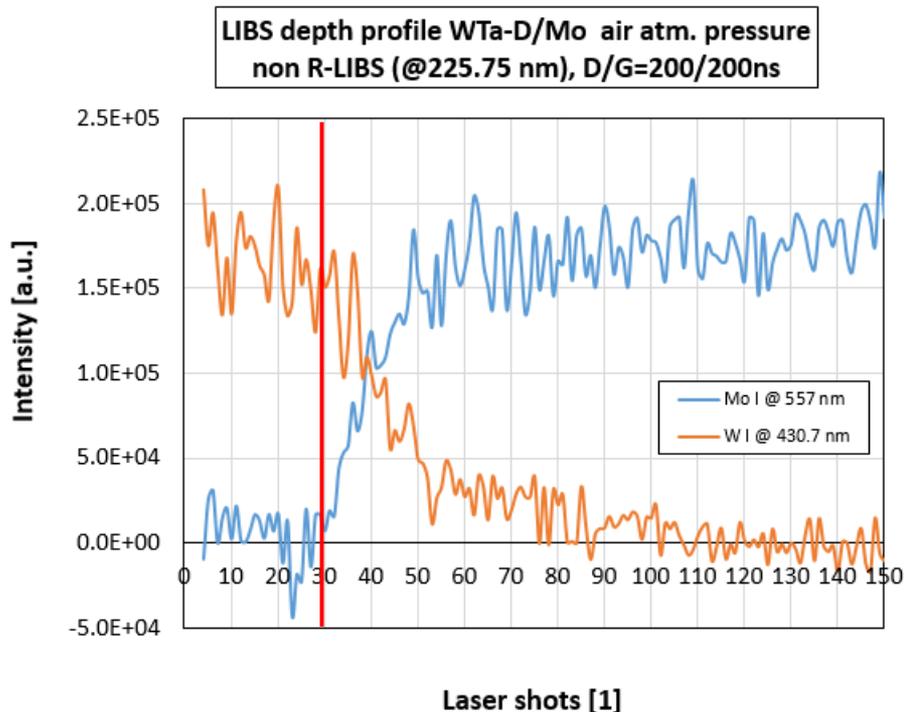
**Laser energy profile at resonance**  
Average energy- 1.43 mJ

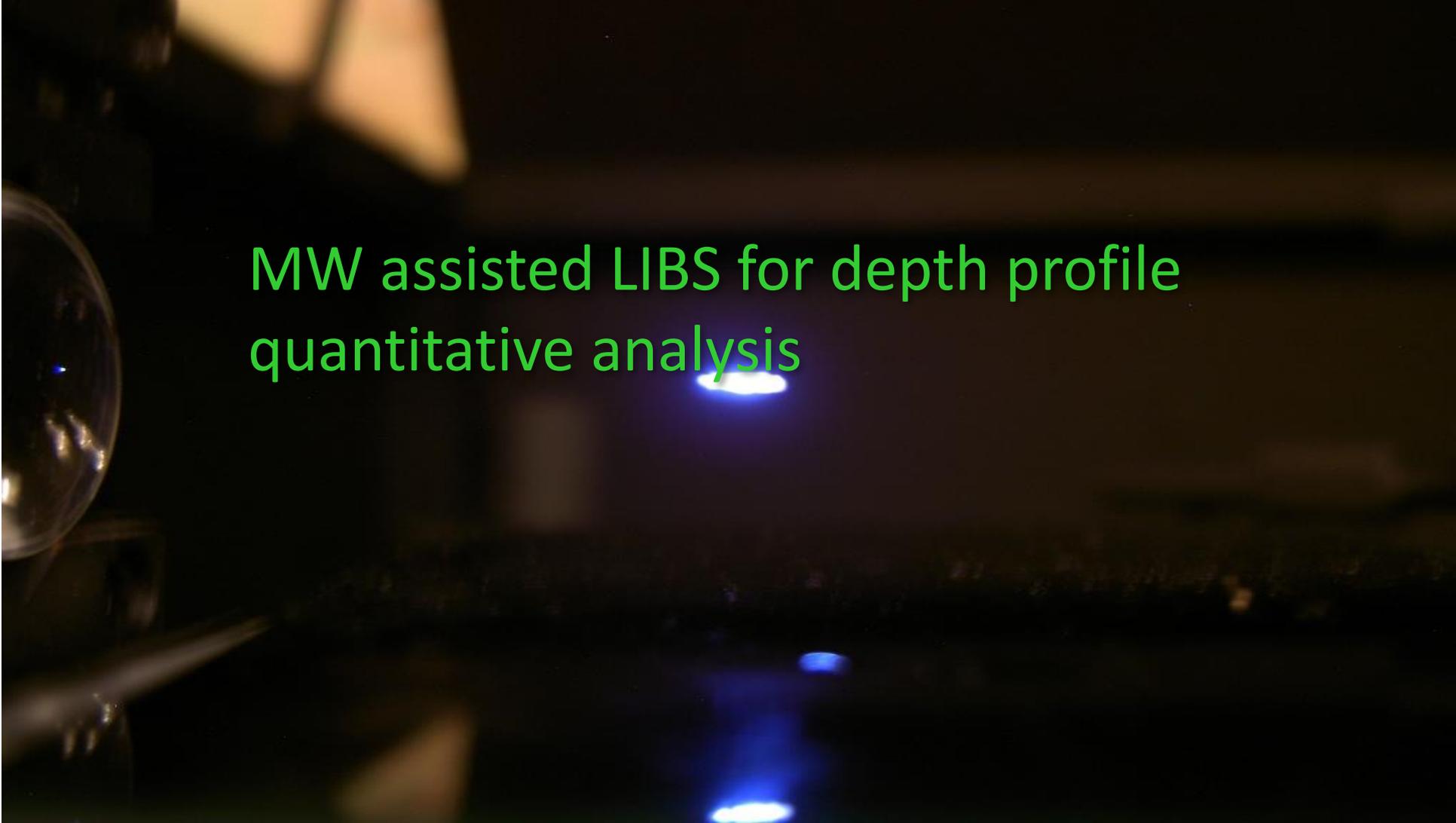


# Resonant - LIBS depth profile analysis of WTa/Mo samples



- ✓ R-LIBS and non R-LIBS depth profile for sample WTa/Mo (4  $\mu\text{m}$ )
- ✓ Ablation rate more than 2 times less in the case of RESONANT LIBS giving the same plasma emission





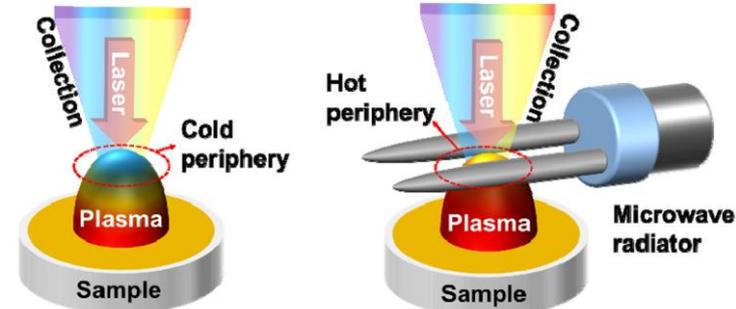
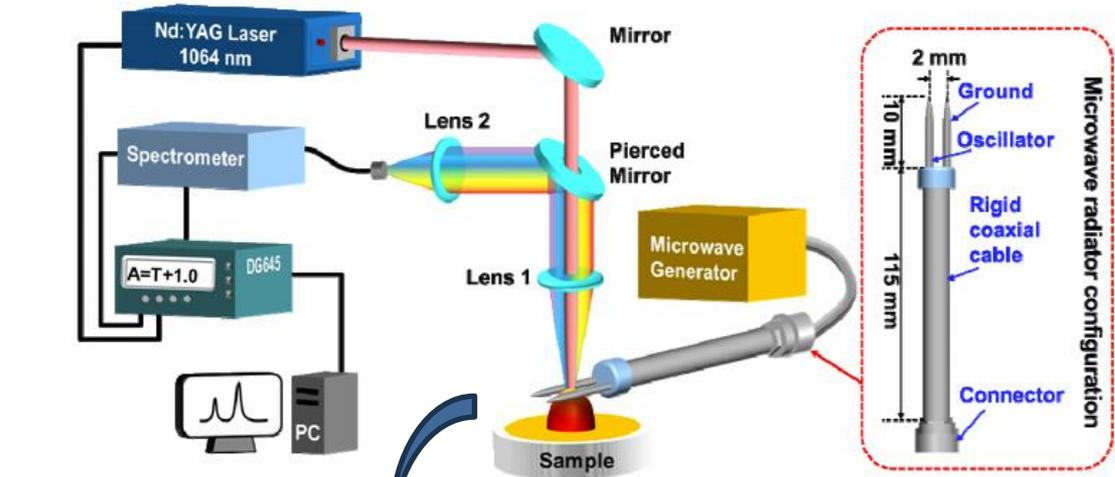
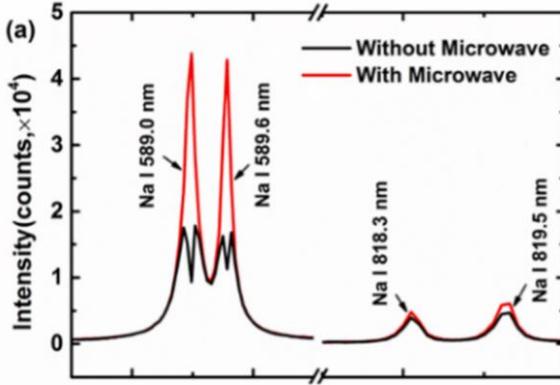
MW assisted LIBS for depth profile  
quantitative analysis

# Microwave assisted LIBS



The presence of the MW radiation:

- 1/ extends the plasma lifetime
- 2/ increases the plasma size
- 3/ resulting in **improvement** in sensitivity **by a factor of 10x to 1000x** depending on the sample
- 4/ and self-absorption reduction.

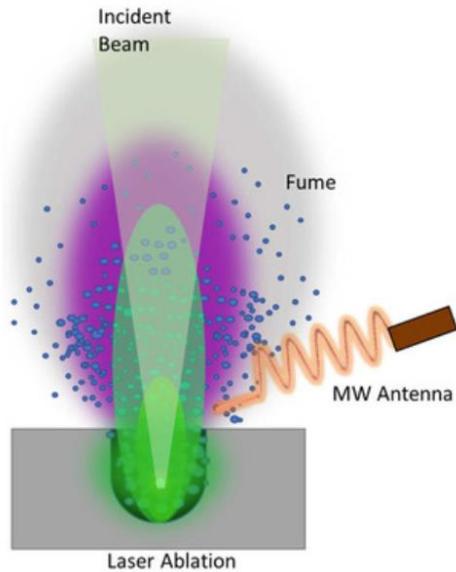


(a) Without microwave

(b) With microwave

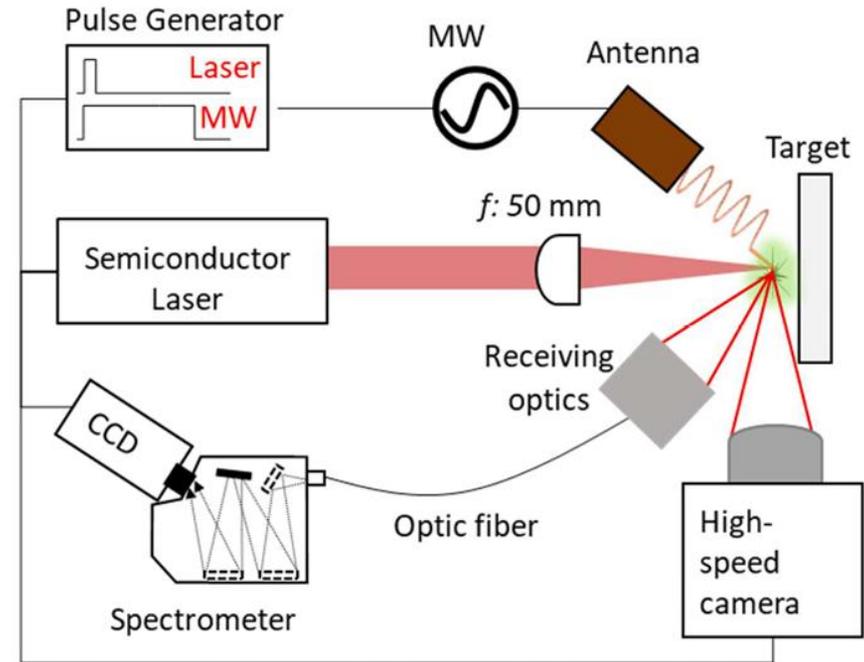
Y. Tang et al., Multielemental self-absorption reduction in LIBS by using MW assisted excitation, OPTICS EXPRESS Vol. 26 (2018) Art. No. 12121

# Microwave assisted LIBS



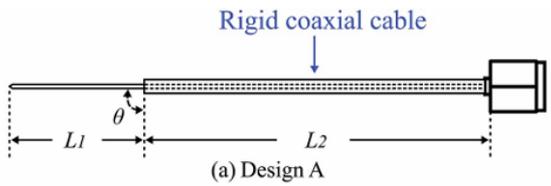
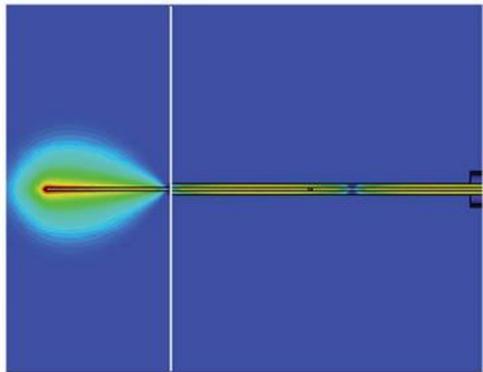
## Different types of the antenna:

- capacitor-like antenna (Antenna No. 1),
- square-shaped flat spiral antenna (Antenna No. 2),
- circular shaped flat spiral antenna (Antenna No. 3),
- octagonal-shaped flat spiral antenna (Antenna No. 4),
- directly mounted helical coil (Antenna No. 5),
- bent-mounted helical coil (Antenna No.6),
- conical spiral antenna with an increasing diameter (Antenna No. 7),
- conical coil with decreasing diameter (Antenna No.8).

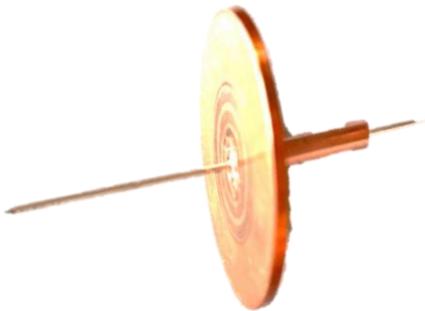


**Y. Ikeda et al., Antenna Characteristics of Helical Coil with 2.45 GHz Semiconductor Microwave for MW-LIBS, Materials 15 (2022) Art.No. 2851**

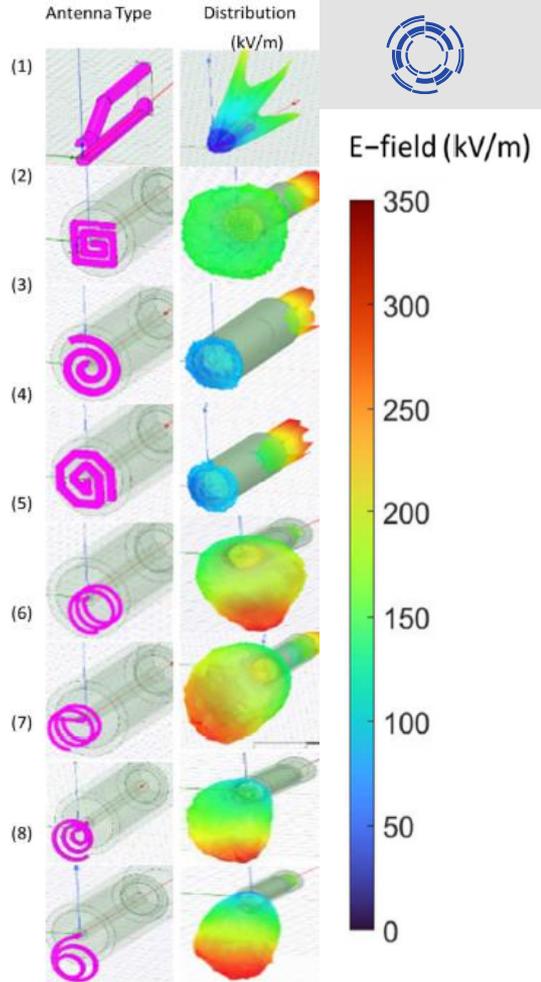
# Microwave assisted LIBS – antenna shape



S.J. Chen, Z.T. Alwahabi et al.,  
JAAS 32 (2017) 1508-1518



S. Soni, P. Veis et al.,  
Comenius Univ.



Y. Ikeda et al., Materials , 15 (2022) 2851.

# Microwave assisted LIBS – solutions, setup

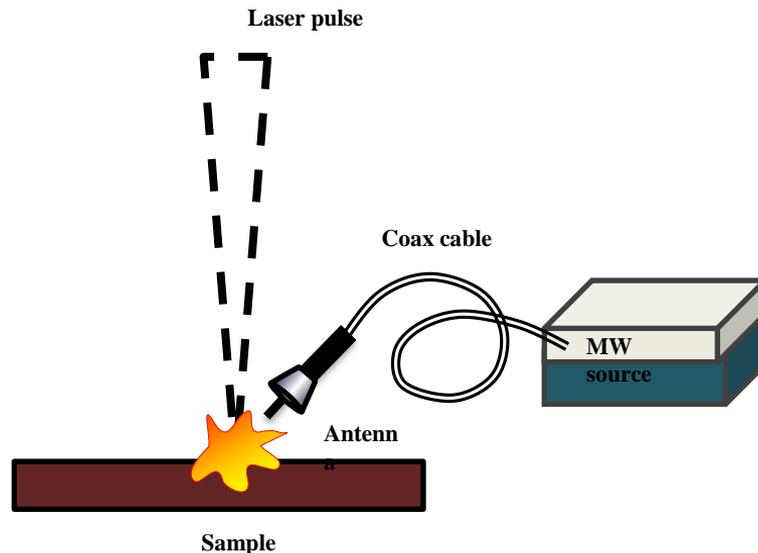
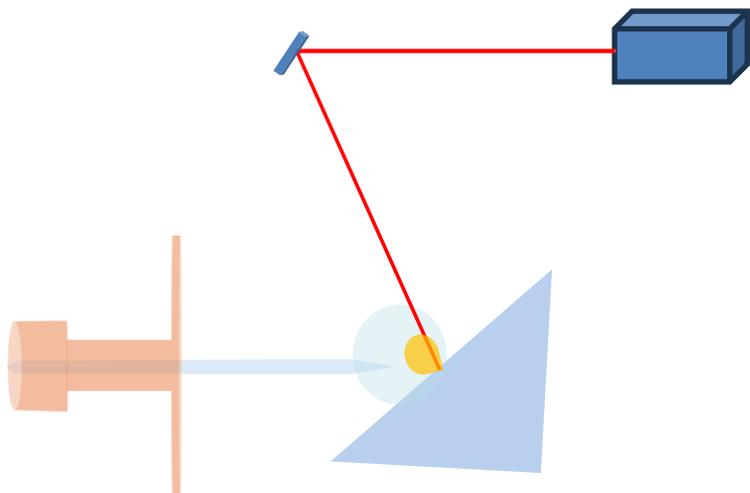


## Microwave sources

### Magnetron source    Solid-state electronics based

Well explored  
High power output  
Bulky  
Expensive  
Less flexibility

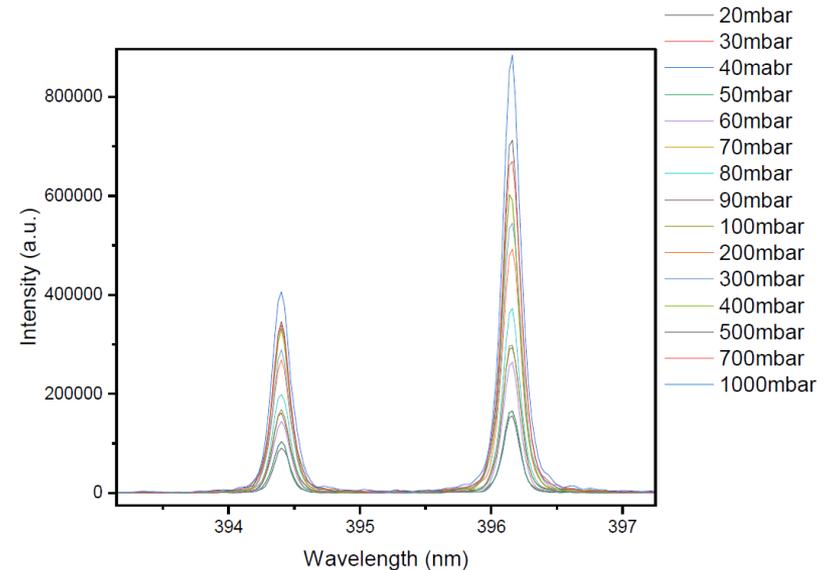
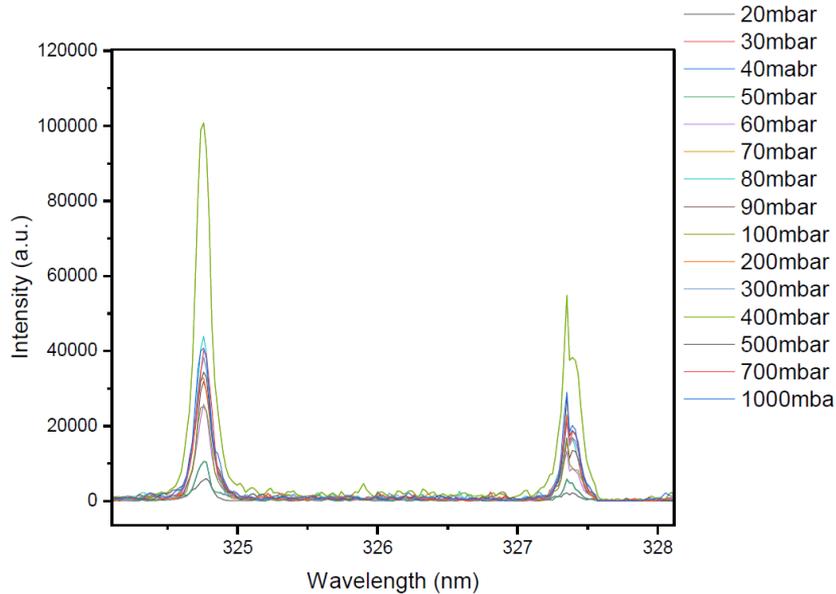
Compact  
Flexible  
Cost-effective  
Antenna based  
Coax cable MWF guiding



# Microwave assisted LIBS – first observations



- The maximum power output = 50W
- $F = 2.434$  GHz



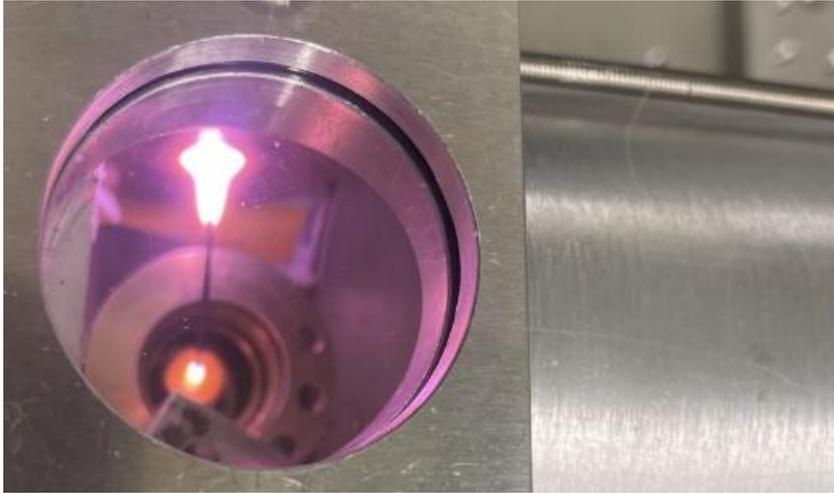
- Detected also Cu sputtered from antenna at different Ar pressure

- Al enhancement with MW-LIBS at different pressure

# Microwave assisted LIBS – photos



- At low Ar pressure



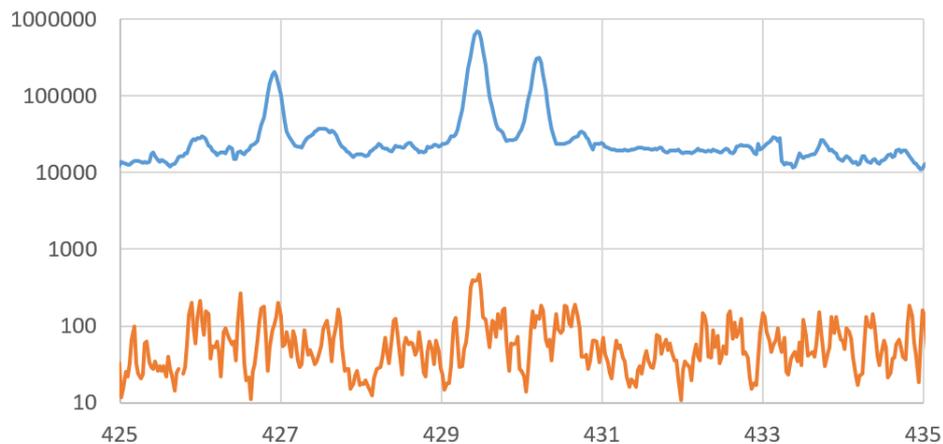
- At atm. Pressure - Ar



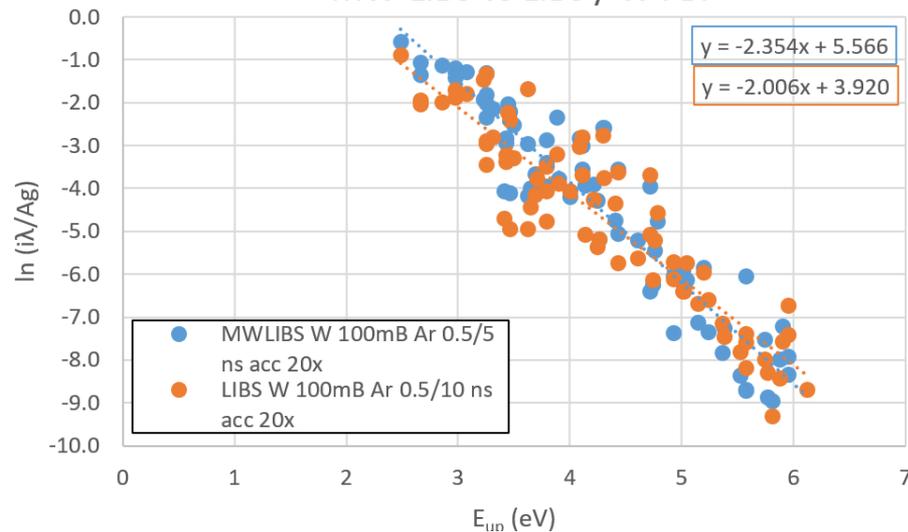
# Microwave assisted LIBS – W sample



MW-LIBS vs LIBS / W sample  
ns laser 1064 nm, 100mB\_Ar acc\_20sh



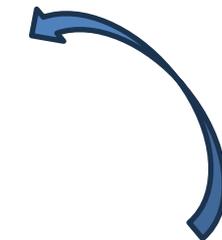
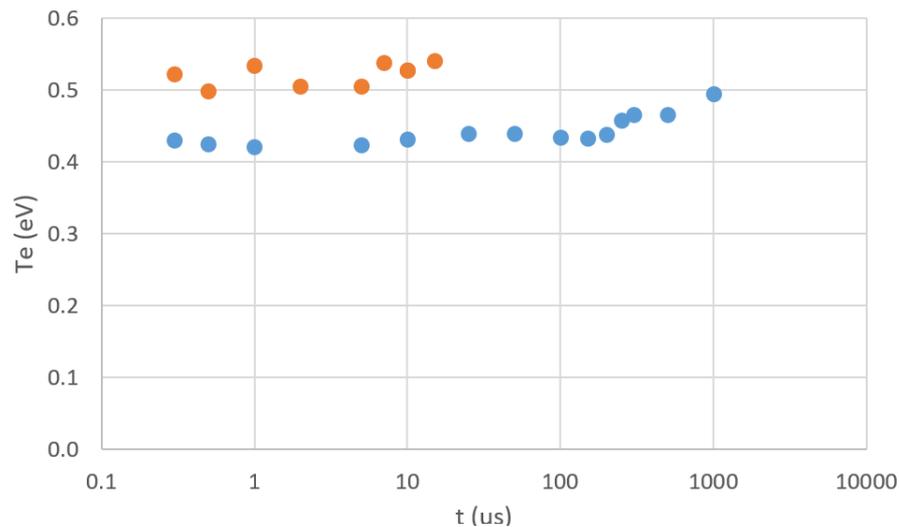
MW-LIBS vs LIBS / W | BP



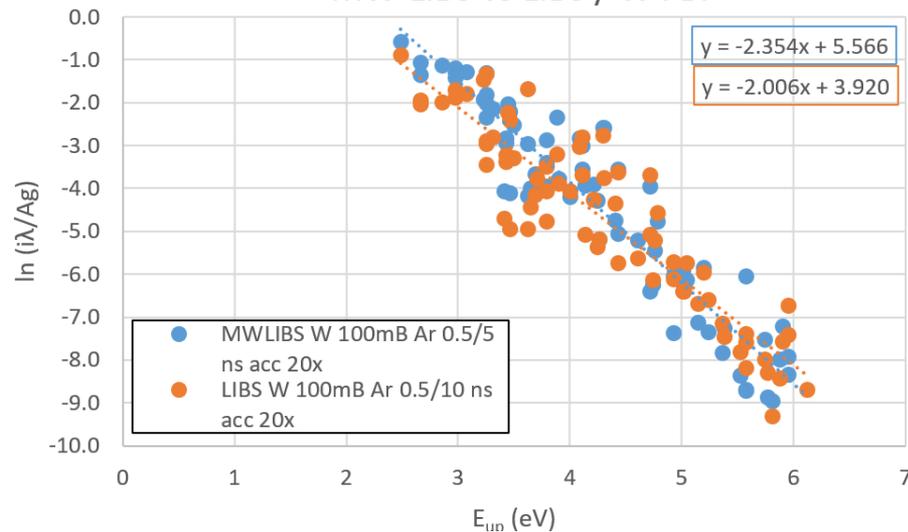
# Microwave assisted LIBS – W sample



MW-LIBS vs LIBS / Te (from BP W I)



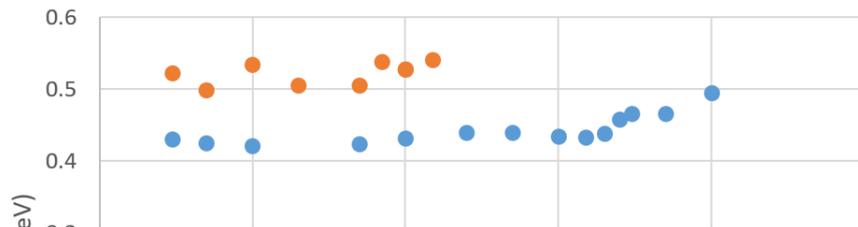
MW-LIBS vs LIBS /  $W$  I BP



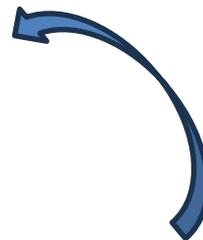
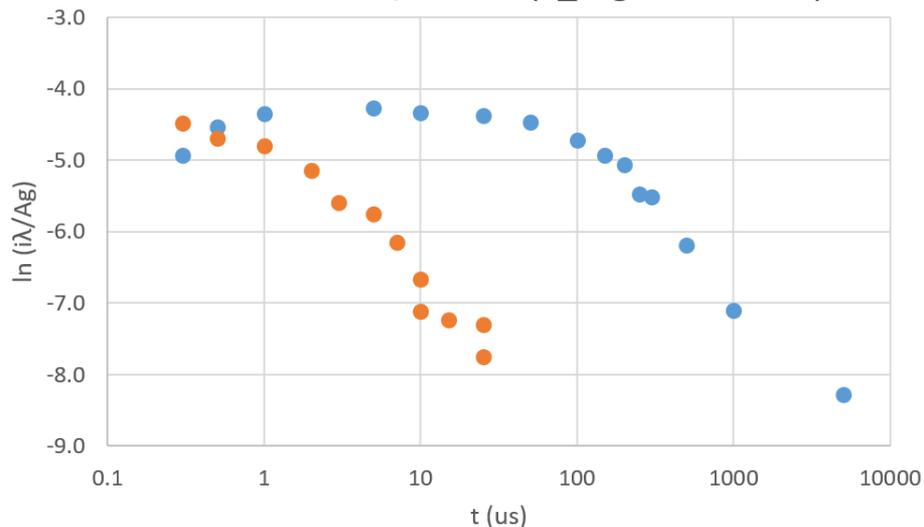
# Microwave assisted LIBS – W sample



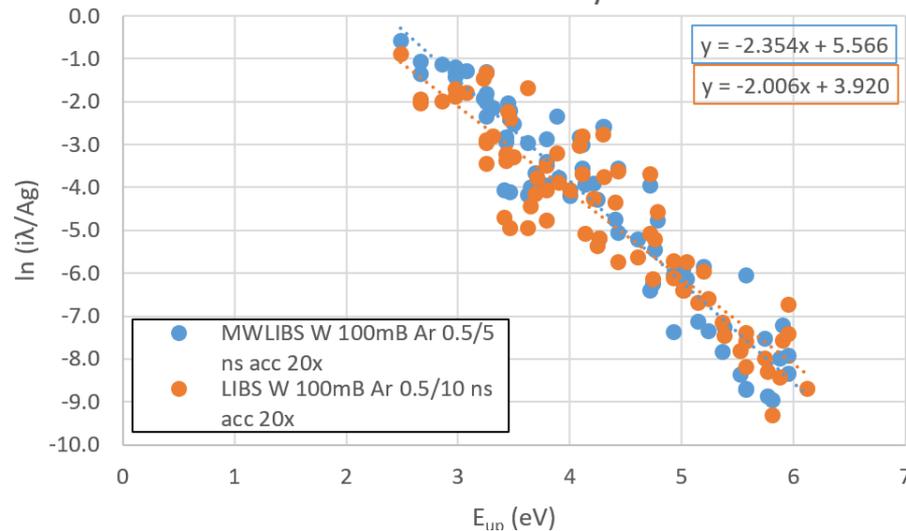
MW-LIBS vs LIBS / Te (from BP W I)



MW-LIBS vs LIBS / W I BP (Y\_avg coordinate)



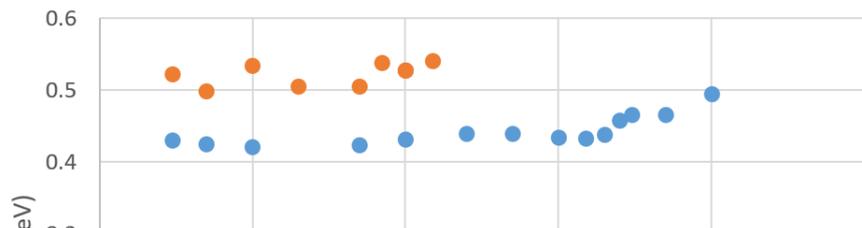
MW-LIBS vs LIBS / W I BP



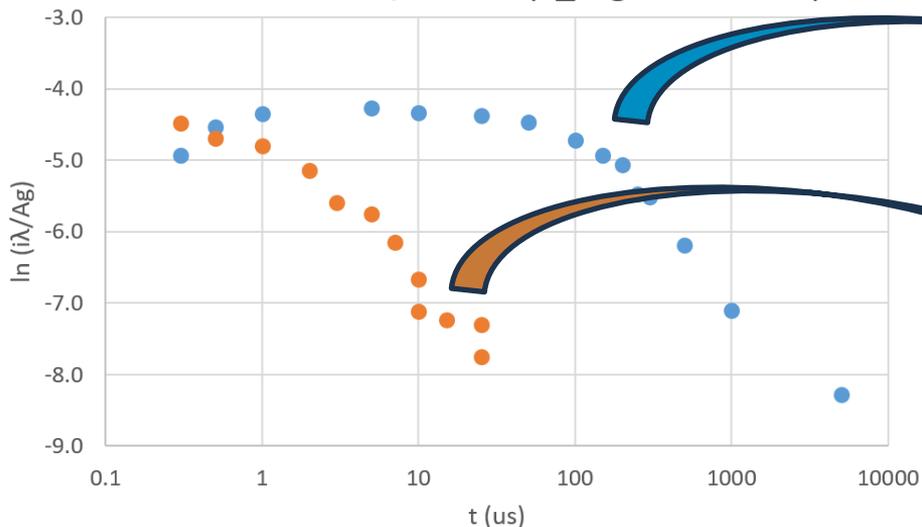
# Microwave assisted LIBS – W sample



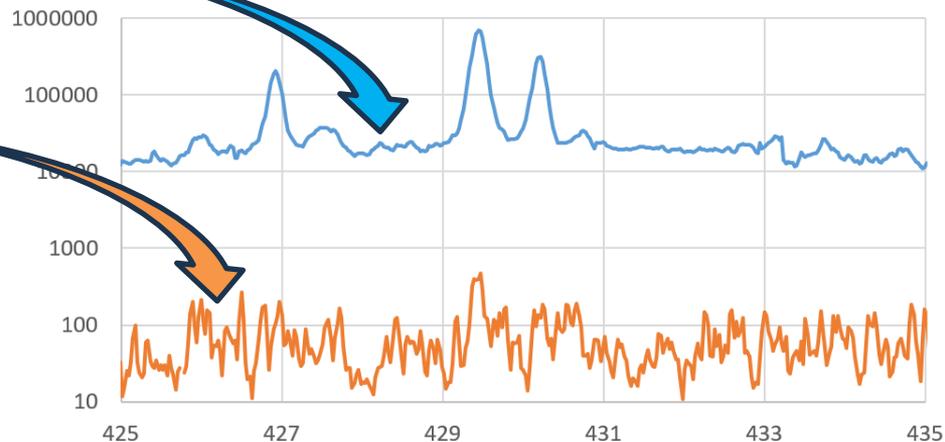
MW-LIBS vs LIBS / Te (from BP W I)



MW-LIBS vs LIBS / W I BP (Y\_avg coordinate)



MW-LIBS vs LIBS / W sample  
ns laser 1064 nm, 100mB\_Ar acc\_20sh



# Conclusion



- **Bulk, surface and depth profile analysis in combination with CF LIBS for quantification at intermediate and atmospheric pressure (including Ha/Da isotope line separation).**
- **Comparison of ps- and ns-LIBS.**
- **Re excitation, improvement of OES and minimisation of ablation rate by Resonant LIBS.**
- **Strong improvement of OES by MW LIBS.**

Thank you very much for your attention!



VTT (Helsinki, Finland)  
A. Hakola,  
J. Karhunen



Tartu Univ, Estonia  
P. Paris,  
M. Laan,  
I. Jogi



FZJ, Jülich, Germany  
S. Brezinsek



DIFFER (Eindhoven)  
H. van der Meiden



JSI, Ljubljana, Slovenia  
V. Nemanic



Bucharest, Romania  
C. Porosnicu,  
C.P. Lungu,  
E. Grigore



Prague, Czech Rep.  
R. Dejarnac



Acknowledgement for financial support: EUROfusion  
Scientific Grant Agency of the Slovak Republic  
Slovak Research and Development Agency

